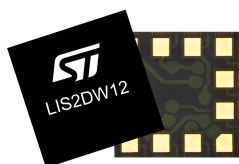


MEMS digital output motion sensor: high-performance ultralow-power 3-axis "femto" accelerometer



LGA-12L
2.0 x 2.0 x 0.7 (max) mm

Product status link

[LIS2DW12](#)

Product summary

| | |
|------------------------|---------------|
| Order code | LIS2DW12TR |
| Temperature range [°C] | -40 to +85 |
| Package | LGA-12 |
| Packing | Tape and reel |

Product resources

[AN5038](#) (device application note)
[TN0018](#) (design and soldering)

Product label



Features

- Ultralow power consumption: 50 nA in power-down mode, below 1 μ A in active low-power mode
- Very low noise: down to 1.3 mg RMS in low-power mode
- Multiple operating modes with multiple bandwidths
- Android stationary detection, motion detection
- Supply voltage, 1.62 V to 3.6 V
- Independent I/O supply
- $\pm 2g/\pm 4g/\pm 8g/\pm 16g$ full scale
- High-speed I²C/SPI digital output interface
- Single data conversion on demand
- 16-bit data output
- Embedded temperature sensor
- Self-test
- 32-level FIFO
- 10000 g high shock survivability
- [ECOPACK](#) and RoHS compliant

Applications

- Motion detection for wearables
- Gesture recognition and gaming
- Motion-activated functions and user interfaces
- Display orientation
- Tap/double-tap recognition
- Free-fall detection
- Smart power saving for handheld devices
- Hearing aids
- Portable healthcare devices
- Wireless sensor nodes
- Motion-enabled metering devices

Description

The **LIS2DW12** is an ultralow-power high-performance 3-axis linear accelerometer belonging to the "femto" family, which leverages on the robust and mature manufacturing processes already used for the production of micromachined accelerometers.

The device has user-selectable full scales of $\pm 2g/\pm 4g/\pm 8g/\pm 16g$ and can measure accelerations with output data rates from 1.6 Hz to 1600 Hz.

The LIS2DW12 has an integrated 32-level first-in, first-out (FIFO) buffer allowing the user to store data in order to limit intervention by the host processor.

The embedded self-test capability allows the user to check the functioning of the sensor in the final application.

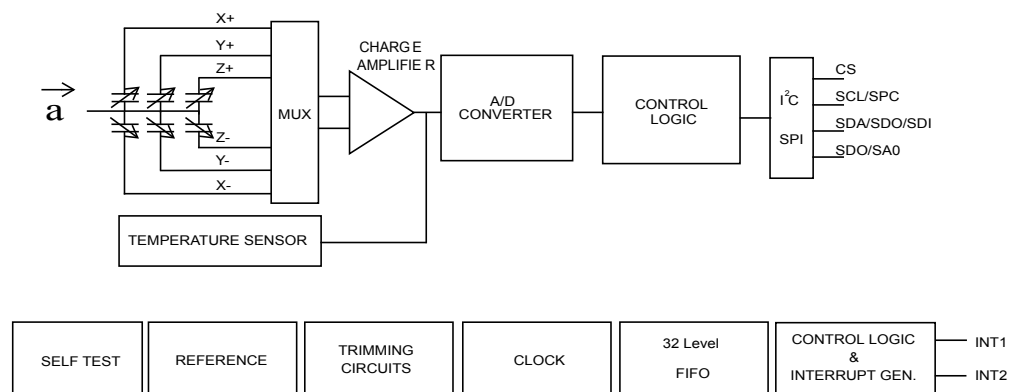
The device has a dedicated internal engine to process motion and acceleration detection including free-fall, wake-up, highly configurable single/double-tap recognition, activity/inactivity, stationary/motion detection, portrait/landscape detection, and 6D/4D orientation.

The LIS2DW12 is available in a small thin plastic, land grid array (LGA) package and it is guaranteed to operate over an extended temperature range from -40°C to +85°C.

1 Block diagram and pin description

1.1 Block diagram

Figure 1. Block diagram



1.2 Pin description

Figure 2. Pin connections

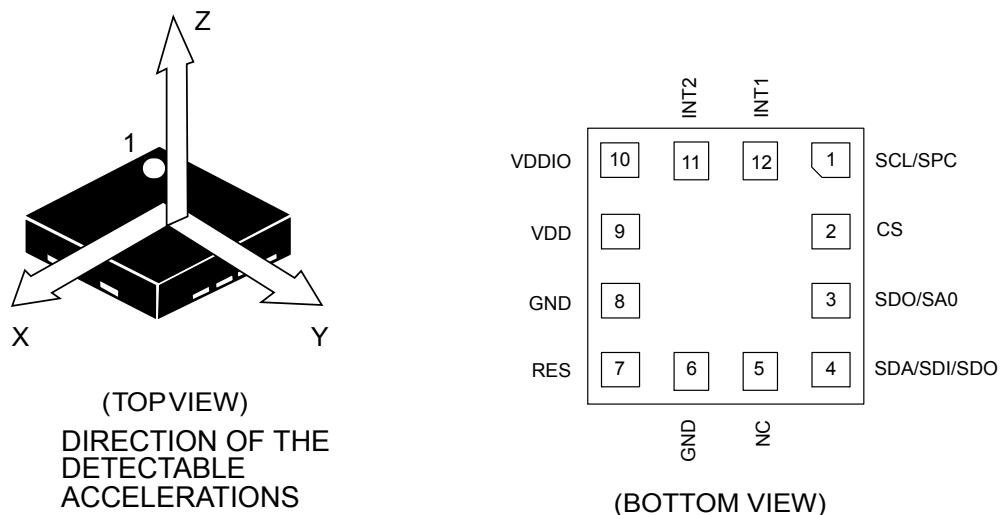


Table 1. Pin description

| Pin# | Name | Function |
|------------------|-------------------|--|
| 1 | SCL SPC | I ² C serial clock (SCL) SPI serial port clock (SPC) |
| 2 ⁽¹⁾ | CS | Enable SPI I ² C/SPI mode selection (1: SPI idle mode / I ² C communication enabled; 0: SPI communication mode / I ² C disabled) |
| 3 ⁽¹⁾ | SDO SA0 | SPI serial data output (SDO) I ² C less significant bit of the device address (SA0) |
| 4 | SDA SDI SDO | I ² C serial data (SDA) SPI serial data input (SDI) 3-wire interface serial data output (SDO) |
| 5 | NC | Internally not connected. Can be tied to VDD, VDDIO, or GND. |
| 6 | GND | 0 V supply |
| 7 | RES | Connect to GND |
| 8 | GND | 0 V supply |
| 9 | VDD | Power supply |
| 10 | VDD_IO | Power supply for I/O pins |
| 11 | INT2 | Interrupt pin 2. Clock input when selected in single data conversion on demand. |
| 12 | INT1 | Interrupt pin 1 |

1. SDO/SA0 and CS pins are internally pulled up. Refer to Table 2. Internal pull-up values (typ.) for SDO/SA0 and CS pins for the internal pull-up values (typ).

Table 2. Internal pull-up values (typ.) for SDO/SA0 and CS pins

| Vdd_IO | Resistor value for SDO/SA0 and CS pins |
|--------|--|
| | Typ. (kΩ) |
| 1.7 V | 54.4 |
| 1.8 V | 49.2 |
| 2.5 V | 30.4 |
| 3.6 V | 20.4 |

2 Mechanical and electrical specifications

2.1 Mechanical characteristics

@Vdd = 1.8 V, T = 25°C unless otherwise noted. The product is factory calibrated at 1.8 V. The operational power supply range is from 1.62 V to 3.6 V.

Table 3. Mechanical characteristics

| Symbol | Parameter | Test conditions | Min. | Typ. ⁽¹⁾ | Max. | Unit |
|--------|---|---|------|---------------------|------|----------|
| FS | Measurement range | | | ±2 | | g |
| | | | | ±4 | | |
| | | | | ±8 | | |
| | | | | ±16 | | |
| So | Sensitivity | @ FS ±2 g in high-performance mode and all low-power modes except low-power mode 1 | | 0.244 | | mg/digit |
| | | @ FS ±4 g in high-performance mode and all low-power modes except low-power mode 1 | | 0.488 | | |
| | | @ FS ±8 g in high-performance mode and all low-power modes except low-power mode 1 | | 0.976 | | |
| | | @ FS ±16 g in high-performance mode and all low-power modes except low-power mode 1 | | 1.952 | | |
| | | @ FS ±2 g in low-power mode 1 | | 0.976 | | |
| | | @ FS ±4 g in low-power mode 1 | | 1.952 | | |
| | | @ FS ±8 g in low-power mode 1 | | 3.904 | | |
| | | @ FS ±16 g in low-power mode 1 | | 7.808 | | |
| An | Noise density - high-performance mode ⁽²⁾ | @ FS ±2 g | | 90 | | μg/√Hz |
| RMS | RMS noise - low-power modes ⁽³⁾ @ FS ±2 g | Low-power mode 4 | | 1.3 | | mg(RMS) |
| | | Low-power mode 3 | | 1.8 | | |
| | | Low-power mode 2 | | 2.4 | | |
| | | Low-power mode 1 | | 4.5 | | |
| TyOff | Zero-g level offset accuracy ⁽⁴⁾ | | | ±20 | | mg |
| TCO | Zero-g offset change vs. temperature | | | ±0.2 | | mg/°C |
| TCS | Sensitivity change vs. temperature | | | 0.01 | | %/°C |
| ST | Self-test positive difference | | 70 | | 1500 | mg |

1. Typical specifications are not guaranteed.
2. Noise density is the same for all ODRs. Low-noise setting enabled.
3. RMS noise is the same for all ODRs. Low-noise setting enabled.
4. Values after factory calibration test and trimming.

2.2 Electrical characteristics

@Vdd = 1.8 V, T = 25°C unless otherwise noted. The product is factory calibrated at 1.8 V. The operational power supply range is from 1.62 V to 3.6 V.

Table 4. Electrical characteristics

| Symbol | Parameter | Test conditions | Min. | Typ. ⁽¹⁾ | Max. | Unit |
|-----------------|--|--|--------------|---------------------|------------|------|
| Vdd | Supply voltage | | 1.62 | 1.8 | 3.6 | V |
| Vdd_IO | I/O pins supply voltage ⁽²⁾ | | 1.62 | | Vdd+0.1 | V |
| IddHR | Supply current in high-performance mode ⁽³⁾ | @ ODR range 12.5 Hz - 1600 Hz, 14-bit | | 90 | | μA |
| IddLP | Supply current in low-power mode ⁽⁴⁾ | ODR 100 Hz | | 5 | | μA |
| | | ODR 50 Hz | | 3 | | |
| | | ODR 12.5 Hz | | 1 | | |
| | | ODR 1.6 Hz | | 0.38 | | |
| Idd_PD | Supply current in power-down | | | 50 | | nA |
| V _{IH} | Digital high-level input voltage | | 0.7*Vdd_IO | | | V |
| V _{IL} | Digital low-level input voltage | | | | 0.3*Vdd_IO | V |
| V _{OH} | Digital high-level output voltage | I _{OH} = 4 mA ⁽⁵⁾ | Vdd_IO - 0.2 | | | V |
| V _{OL} | Digital low-level output voltage | I _{OL} = 4 mA ⁽⁵⁾ | | | 0.2 | V |

1. Typical specifications are not guaranteed.
2. It is possible to remove Vdd maintaining Vdd_IO without blocking the communication busses. In this condition the measurement chain is powered off.
3. Low-noise setting disabled.
4. Low-power mode 1. Low-noise setting disabled.
5. 4 mA is the maximum driving capability, that is, the maximum DC current that can be sourced/sunk by the digital pad in order to guarantee the correct digital output voltage levels V_{OH} and V_{OL}.

2.3 Temperature sensor characteristics

@Vdd = 1.8 V, T = 25°C unless otherwise noted

Table 5. Temperature sensor characteristics

| Symbol | Parameter | Min. | Typ. ⁽¹⁾ | Max. | Unit |
|--------|--|------|---------------------|------|--------|
| Top | Operating temperature range | -40 | | +85 | °C |
| Toff | Temperature offset ⁽²⁾ | -15 | | +15 | °C |
| TSDr | Temperature sensor output change vs. temperature | | 1 ⁽³⁾ | | LSB/°C |
| | | | 16 ⁽⁴⁾ | | |
| TODR | Temperature refresh rate in high-performance mode for all ODRs or in low-power modes for ODRs equal to 200/100/50 Hz | | 50 | | Hz |
| | Temperature refresh rate in low-power modes for ODR equal to 25 Hz | | 25 | | |
| | Temperature refresh rate in low-power modes for ODR equal to 12.5 Hz | | 12.5 | | |
| | Temperature refresh rate in low-power modes for ODR equal to 1.6 Hz | | 1.6 | | |

1. Typical specifications are not guaranteed.
2. The output of the temperature sensor is 0 LSB (typ.) at 25°C.
3. 8-bit resolution.
4. 12-bit resolution.

2.4 Communication interface characteristics

2.4.1 SPI - serial peripheral interface

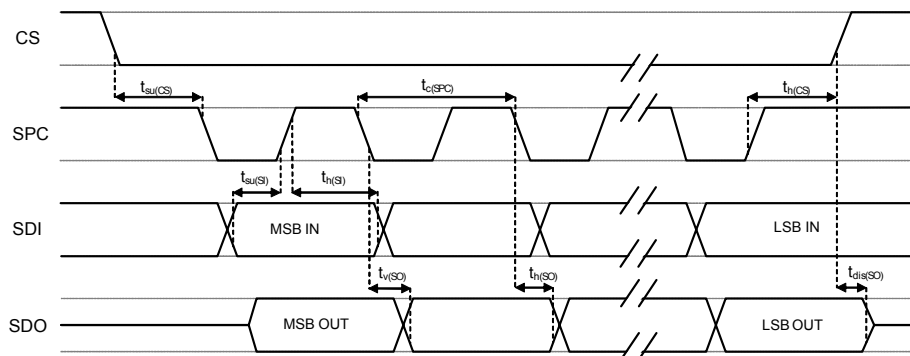
Subject to general operating conditions for Vdd and Top.

Table 6. SPI slave timing values

| Symbol | Parameter | Value ⁽¹⁾ | | Unit |
|---------------|-------------------------|----------------------|-----|------|
| | | Min | Max | |
| $t_{c(SPC)}$ | SPI clock cycle | 100 | | ns |
| $f_{c(SPC)}$ | SPI clock frequency | | 10 | MHz |
| $t_{su(CS)}$ | CS setup time | 6 | | ns |
| $t_{h(CS)}$ | CS hold time | 8 | | |
| $t_{su(SI)}$ | SDI input setup time | 12 | | |
| $t_{h(SI)}$ | SDI input hold time | 15 | | |
| $t_{v(SO)}$ | SDO valid output time | | 50 | |
| $t_{h(SO)}$ | SDO output hold time | 9 | | |
| $t_{dis(SO)}$ | SDO output disable time | | 50 | |

1. 10 MHz clock frequency for SPI with both 4 and 3 wires, based on characterization results, not tested in production.

Figure 3. SPI slave timing diagram



Note: Measurement points are done at $0.3 \cdot V_{dd_IO}$ and $0.7 \cdot V_{dd_IO}$ for both input and output ports.

2.4.2 I²C - inter-IC control interface

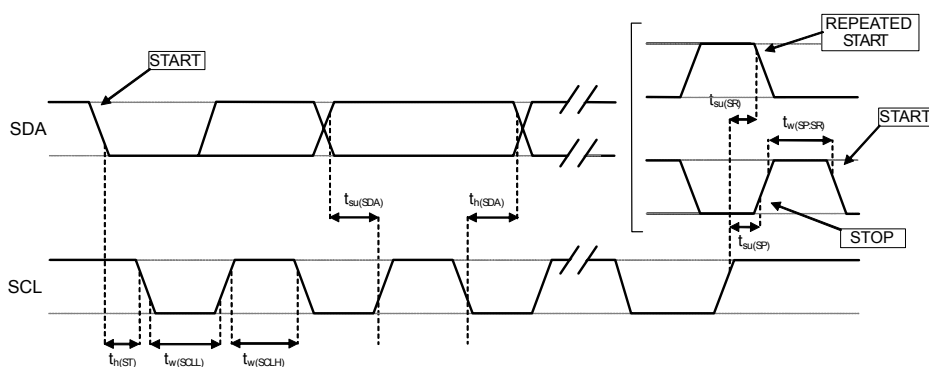
Subject to general operating conditions for V_{dd} and T_{op}.

Table 7. I²C slave timing values

| Symbol | Parameter | I ² C standard mode ⁽¹⁾ | | I ² C fast mode ⁽¹⁾ | | Unit |
|-----------------------|--|---|------|---|-----|------|
| | | Min | Max | Min | Max | |
| f _(SCL) | SCL clock frequency | 0 | 100 | 0 | 400 | kHz |
| t _{w(SCLL)} | SCL clock low time | 4.7 | | 1.3 | | μs |
| t _{w(SCLH)} | SCL clock high time | 4.0 | | 0.6 | | |
| t _{su(SDA)} | SDA setup time | 250 | | 100 | | ns |
| t _{h(SDA)} | SDA data hold time | 0.01 | 3.45 | 0.01 | 0.9 | μs |
| t _{h(ST)} | START condition hold time | 4 | | 0.6 | | μs |
| t _{su(SR)} | Repeated START condition setup time | 4.7 | | 0.6 | | |
| t _{su(SP)} | STOP condition setup time | 4 | | 0.6 | | |
| t _{w(SP:SR)} | Bus free time between STOP and START condition | 4.7 | | 1.3 | | |

1. Data based on standard I²C protocol requirement, not tested in production.

Figure 4. I²C slave timing diagram



Note: Measurement points are done at 0.3·V_{dd_IO} and 0.7·V_{dd_IO} for both ports.

Table 8. I²C high-speed mode specifications at 1 MHz and 3.4 MHz

| Mode | Symbol | Parameter | Min | Max | Unit |
|--------------------------------|---------------------|--|-------------------------|-----|------|
| Fast mode plus ⁽¹⁾ | f _{SCL} | SCL clock frequency | 0 | 1 | MHz |
| | t _{HD;STA} | Hold time (repeated) START condition | 260 | - | ns |
| | t _{LOW} | Low period of the SCL clock | 500 | - | |
| | t _{HIGH} | High period of the SCL clock | 260 | - | |
| | t _{SU;STA} | Setup time for a repeated START condition | 260 | - | |
| | t _{HD;DAT} | Data hold time | 0 | - | |
| | t _{SU;DAT} | Data setup time | 50 | - | |
| | t _{rDA} | Rise time of SDA signal | - | 120 | |
| | t _{fDA} | Fall time of SDA signal | - | 120 | |
| | t _{rCL} | Rise time of SCL signal | 20*V _{dd} /5.5 | 120 | |
| | t _{fCL} | Fall time of SCL signal | 20*V _{dd} /5.5 | 120 | |
| | t _{SU;STO} | Setup time for STOP condition | 260 | - | pF |
| | C _b | Capacitive load for each bus line | - | 550 | |
| | t _{VD;DAT} | Data valid time | - | 450 | |
| | t _{VD;ACK} | Data valid acknowledge time | - | 450 | |
| | V _{nL} | Noise margin at low level | 0.1V _{dd} | - | V |
| | V _{nH} | Noise margin at high level | 0.2V _{dd} | - | |
| | t _{SP} | Pulse width of spikes that must be suppressed by the input filter | 0 | 50 | ns |
| High-speed mode ⁽¹⁾ | f _{SCLH} | SCLH clock frequency | 0 | 3.4 | MHz |
| | t _{SU;STA} | Setup time for a repeated START condition | 160 | - | ns |
| | t _{HD;STA} | Hold time (repeated) START condition | 160 | - | |
| | t _{LOW} | Low period of the SCLH clock | 160 | - | |
| | t _{HIGH} | High period of the SCLH clock | 60 | - | |
| | t _{SU;DAT} | Data setup time | 10 | - | |
| | t _{HD;DAT} | Data hold time | 0 | 70 | |
| | t _{rCL} | Rise time of SCLH signal | 10 | 40 | |
| | t _{rCL1} | Rise time of SCLH signal after a repeated START condition and after an acknowledge bit | 10 | 80 | |
| | t _{fCL} | Fall time of SCLH signal | 10 | 40 | |
| | t _{rDA} | Rise time of SDAH signal | 10 | 80 | pF |
| | t _{fDA} | Fall time of SDAH signal | 10 | 80 | |
| | t _{SU;STO} | Setup time for STOP condition | 160 | - | |
| | C _b | Capacitive load for each bus line | - | 100 | |
| | V _{nH} | Noise margin at high level | 0.2V _{dd} | - | V |
| | t _{SP} | Pulse width of spikes that must be suppressed by the input filter | 0 | 10 | ns |

1. Data based on characterization, not tested in production.

2.5 Absolute maximum ratings

Stresses above those listed as “absolute maximum ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 9. Absolute maximum ratings

| Symbol | Ratings | Maximum value | Unit |
|--------------------|--|----------------------------------|------|
| V _{DD} | Supply voltage | -0.3 to 4.8 | V |
| V _{DD_IO} | I/O pins supply voltage | -0.3 to 4.8 | V |
| V _{IN} | Input voltage on any control pin (CS, SCL/SPC, SDA/SDI/SDO, SDO/SA0) | -0.3 to V _{DD_IO} + 0.3 | V |
| A _{POW} | Acceleration (any axis, powered, V _{DD} = 1.8 V) | 3000 g for 0.5 ms | g |
| | | 10000 g for 0.2 ms | g |
| A _{UNP} | Acceleration (any axis, unpowered) | 3000 g for 0.5 ms | g |
| | | 10000 g for 0.2 ms | g |
| T _{OP} | Operating temperature range | -40 to +85 | °C |
| T _{STG} | Storage temperature range | -40 to +125 | °C |
| ESD | Electrostatic discharge protection | 2 (HBM) | kV |

Note: Supply voltage on any pin should never exceed 4.8 V.



This device is sensitive to mechanical shock, improper handling can cause permanent damage to the part.



This device is sensitive to electrostatic discharge (ESD), improper handling can cause permanent damage to the part.

3 Terminology and functionality

3.1 Terminology

3.1.1 Sensitivity

Sensitivity describes the gain of the sensor and can be determined by applying 1 *g* acceleration to it. As the sensor can measure DC accelerations this can be done easily by pointing the axis of interest towards the center of the Earth, noting the output value, rotating the sensor by 180 degrees (pointing to the sky) and noting the output value again. By doing so, ± 1 *g* acceleration is applied to the sensor. Subtracting the larger output value from the smaller one, and dividing the result by 2, leads to the actual sensitivity of the sensor. This value changes very little over temperature and time. The sensitivity tolerance describes the range of sensitivities of a large population of sensors.

3.1.2 Zero-g level offset

Zero-*g* level offset describes the deviation of an actual output signal from the ideal output signal if no acceleration is present. A sensor in a steady state on a horizontal surface measures 0 *g* on the X-axis and 0 *g* on the Y-axis whereas the Z-axis measures 1 *g*. The output is ideally in the middle of the dynamic range of the sensor (content of OUT registers 00h, data expressed as two's complement number). A deviation from the ideal value in this case is called zero-*g* level offset. Offset is to some extent a result of stress to the MEMS sensor and therefore the offset can slightly change after mounting the sensor onto a printed circuit board or exposing it to extensive mechanical stress. Offset changes little over temperature, see "Zero-*g* level offset change vs. temperature".

3.2 Functionality

3.2.1 Operating modes

Two sets of operating modes have been designed to offer the customer a broad choice of noise/power consumption combinations:

- Low-noise disabled (see [Table 10. Operating modes - low-noise setting disabled](#))
- Low-noise enabled (see [Table 11. Operating modes - low-noise setting enabled](#))

Writing the LOW_NOISE bit in [CTRL6 \(25h\)](#) selects the operating mode (low-noise).

From each of these two sets, five operating modes have been designed:

- One high-performance mode: focus on low noise
- Four low-power modes: trade-off between noise and power consumption

These operating modes are selected by writing the MODE[1:0] and LP_MODE[1:0] bits in [CTRL1 \(20h\)](#).

Table 10. Operating modes - low-noise setting disabled

| Parameter | | High-performance mode | Low-power mode 4 | Low-power mode 3 | Low-power mode 2 | Low-power mode 1 |
|---|-------------------------|---|------------------------------------|------------------------------------|------------------------------------|-------------------------------------|
| Resolution [bit] | | 14-bit | 14-bit | 14-bit | 14-bit | 12-bit |
| ODR [Hz] | | 12.5 - 1600 | 1.6 - 200 | 1.6 - 200 | 1.6 - 200 | 1.6 - 200 |
| BW [Hz] | | ODR/2 (N/A for 1600 Hz), ODR/4, ODR/10, ODR/20 | 180 ODR/4, ODR/10, ODR/20 | 360 ODR/4, ODR/10, ODR/20 | 720 ODR/4, ODR/10, ODR/20 | 3200 ODR/4, ODR/10, ODR/20 |
| Noise density [$\mu\text{g}/\sqrt{\text{Hz}}$] @FS = $\pm 2\text{ g}$, ODR = 200 Hz | | 110 | 160 | 210 | 300 | 550 |
| Supply current [μA] @Vdd=1.8 V | ODR = 1.6 Hz | - | 0.65 | 0.55 | 0.45 | 0.38 |
| | ODR = 12.5 Hz | 90 | 4 | 2.5 | 1.6 | 1 |
| | ODR = 25 Hz | 90 | 8.5 | 4.5 | 3 | 1.5 |
| | = 50 Hz | 90 | 16 | 9 | 5.5 | 3 |
| | ODR = 100 Hz | 90 | 32 | 17.5 | 10.5 | 5 |
| | ODR = 200 Hz | 90 | 63 | 34.5 | 20.5 | 10 |
| | ODR = 400, 800, 1600 Hz | 90 | - | - | - | - |

Table 11. Operating modes - low-noise setting enabled

| Parameter | | High-performance mode | Low-power mode 4 | Low-power mode 3 | Low-power mode 2 | Low-power mode 1 |
|---|-------------------------|---|------------------------------------|------------------------------------|------------------------------------|-------------------------------------|
| Resolution [bit] | | 14-bit | 14-bit | 14-bit | 14-bit | 12-bit |
| ODR [Hz] | | 12.5 - 1600 | 1.6 - 200 | 1.6 - 200 | 1.6 - 200 | 1.6 - 200 |
| BW [Hz] | | ODR/2 (N/A for 1600 Hz), ODR/4, ODR/10, ODR/20 | 180 ODR/4, ODR/10, ODR/20 | 360 ODR/4, ODR/10, ODR/20 | 720 ODR/4, ODR/10, ODR/20 | 3200 ODR/4, ODR/10, ODR/20 |
| Noise density [$\mu\text{g}/\sqrt{\text{Hz}}$] @FS = $\pm 2\text{ g}$, ODR = 200 Hz | | 90 | 130 | 180 | 240 | 450 |
| Supply current [μA] @Vdd=1.8 V | ODR = 1.6 Hz | - | 0.7 | 0.6 | 0.5 | 0.4 |
| | ODR = 12.5 Hz | 120 | 5 | 3 | 2 | 1.1 |
| | ODR = 25 Hz | 120 | 10 | 6 | 3.5 | 2 |
| | ODR = 50 Hz | 120 | 20 | 11 | 7 | 3.5 |
| | ODR = 100 Hz | 120 | 39 | 21.5 | 13 | 6 |
| | ODR = 200 Hz | 120 | 77 | 42 | 25 | 12 |
| | ODR = 400, 800, 1600 Hz | 120 | - | - | - | - |

3.2.2 Single data conversion on-demand mode

The device features a single data conversion on-demand mode that is valid for both sets of operating modes (low-noise disabled or enabled) in the four low-power modes. This mode is enabled by writing the MODE[1:0] bits to 10 in [CTRL1 \(20h\)](#). Low power modes are selected by writing the LP_MODE[1:0] bits in [CTRL1 \(20h\)](#).

The trigger for output data generation can be managed through the I²C/SPI or by applying a clock signal on the INT2 pin acting here as an input by writing the SLP_MODE_SEL bit in [CTRL3 \(22h\)](#):

- When SLP_MODE_SEL = 0, output data generation is triggered by the clock signal on the INT2 pin (see [Figure 5. Single data conversion on-demand functionality](#)).
- When SLP_MODE_SEL = 1, output data generation starts when the SLP_MODE_1 bit is set to 1 logic through the I²C/SPI. When XL data are available in the registers, this bit is automatically set to 0 and the device is ready for another triggered session.

Output data are generated according to the selected low-power mode.

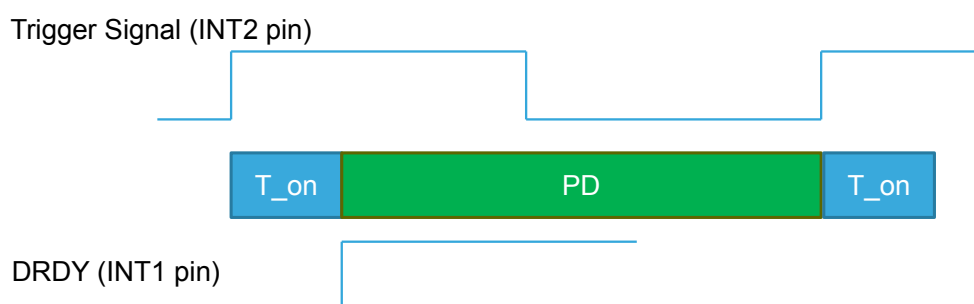
When output data is saved in an output register or FIFO, the device goes to power-down mode and waits for a new trigger.

All ODRs in the range from 0 to up to 200 Hz are supported due to the INT2 clock input.

A DRDY signal or FIFO flags are available on the INT1 pin.

Power consumption is the same as that of standard low-power modes for the same ODR.

Figure 5. Single data conversion on-demand functionality



At the end of turn-on time T_{on} , the DRDY interrupt is activated, output data are available to be read and the device goes into power-down. T_{on} values depend on the low-power mode as follows:

T_{on} (typ.) =

- 1.20 ms for low-power mode 1
- 1.70 ms for low-power mode 2
- 2.30 ms for low-power mode 3
- 3.55 ms for low-power mode 4

3.2.3 Self-test

The self-test allows checking the sensor functionality without moving it. The self-test function is off when the self-test bits (ST) are programmed to 00. When the self-test bits are changed, an actuation force is applied to the sensor, simulating a definite input acceleration. In this case, the sensor outputs exhibit a change in their DC levels, which are related to the selected full scale through the device sensitivity. When the self-test is activated, the device output level is given by the algebraic sum of the signals produced by the acceleration acting on the sensor and by the electrostatic test-force. If the output signals change within the amplitude specified in [Table 3. Mechanical characteristics](#), then the sensor is working properly and the parameters of the interface chip are within the defined specifications.

3.2.4 Activity/Inactivity, Android stationary/motion-detection functions

The activity/inactivity function recognizes the device's sleep state and allows reducing system power consumption.

When the activity/inactivity function is activated by setting the INTERRUPTS_ENABLE bit in [CTRL7 \(3Fh\)](#) and the SLEEP_ON bit in [WAKE_UP_THS \(34h\)](#), the LIS2DW12 automatically goes to 12.5 Hz ODR in the low-power mode previously selected by the LP_MODE[1:0] bits in [CTRL1 \(20h\)](#) if the sleep state condition is detected and wakes up as soon as the interrupt event has been detected, increasing the output data rate and bandwidth.

With this feature the system may be efficiently switched from low-power mode to full performance depending on user-selectable positioning and acceleration events, thus ensuring power saving and flexibility.

The Android stationary/motion detection function only recognizes the device's sleep state.

When the Android stationary/motion-detection function is activated by setting the STATIONARY bit in [WAKE_UP_DUR \(35h\)](#), the LIS2DW12 detects acceleration below a fixed threshold but does not change either ODR or operating mode (high-performance mode or low-power mode) after sleep state detection.

The activity/inactivity recognition function can use the high-pass filter or the offset outputs, this choice can be made through the USR_OFF_ON_OUT bit in [CTRL7 \(3Fh\)](#).

If the device is in sleep (inactivity/stationary) mode, when at least one of the axes exceeds the threshold in [WAKE_UP_THS \(34h\)](#), the device goes into a sleep-to-wake state (as wake-up).

For the activity/inactivity function, the device, in a wake-up state, returns to the operating mode (HP or LP) and ODR before sleep state detection.

Activity/inactivity, Android stationary/motion-detection threshold and duration can be configured in the following control registers:

[WAKE_UP_THS \(34h\)](#)

[WAKE_UP_DUR \(35h\)](#)

3.2.5 High tap/double-tap user configurability

The device embeds the possibility to select the following parameters:

- single axis or multiple axes in [TAP_THS_Z \(32h\)](#)
- axis priority in [TAP_THS_Y \(31h\)](#)
- threshold value of each axis in [TAP_THS_X \(30h\)](#), [TAP_THS_Y \(31h\)](#), and [TAP_THS_Z \(32h\)](#)
- max time threshold between two consecutive taps for double-tap recognition, min time threshold between two consecutive taps to detect a new tap event in [INT_DUR \(33h\)](#)

3.2.6 Offset management

The user can manage the offset in the output or for wake-up detection using dedicated embedded hardware (see [Section 5.1: Block diagram of filters](#)).

3.3 Sensing element

A proprietary process is used to create a surface micromachined accelerometer. The technology allows processing suspended silicon structures, which are attached to the substrate in a few points called anchors and are free to move in the direction of the sensed acceleration. In order to be compatible with the traditional packaging techniques, a cap is placed on top of the sensing element to avoid blocking the moving parts during the molding phase of the plastic encapsulation. When an acceleration is applied to the sensor, the proof mass displaces from its nominal position, causing an imbalance in the capacitive half-bridge. This imbalance is measured using charge integration in response to a voltage pulse applied to the capacitor.

At steady-state the nominal value of the capacitors are a few pF and when an acceleration is applied, the maximum variation of the capacitive load is in the fF range.

3.4 IC interface

The complete measurement chain is composed of a low-noise capacitive amplifier, which converts the capacitive unbalancing of the MEMS sensor into an analog voltage using an analog-to-digital converter.

The acceleration data may be accessed through an I²C/SPI interface thus making the device particularly suitable for direct interfacing with a microcontroller.

The LIS2DW12 features a data-ready signal, which indicates when a new set of measured acceleration data is available, thus simplifying data synchronization in the digital system that uses the device.

3.5 Factory calibration

The IC interface is factory-calibrated for sensitivity (So) and zero-g level offset.

The trim values are stored inside the device in nonvolatile memory. Anytime the device is turned on, the trimming parameters are downloaded into the registers to be used during active operation. This allows using the device without further calibration. If an accidental write occurs in the registers where trimming parameters are stored, the BOOT bit in [CTRL2 \(21h\)](#) can help to retrieve the correct trimming parameters from nonvolatile memory without the need to switch on/off the device. This bit is automatically reset at the end of the download operation. Setting this bit has no impact on the control registers.

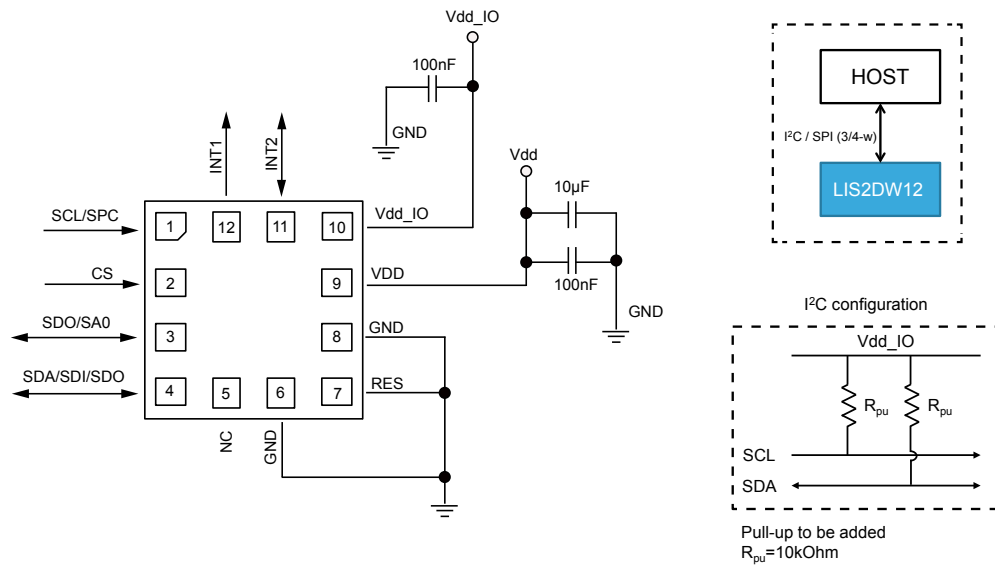
3.6 Temperature sensor

The temperature is available in [OUT_T_L \(0Dh\)](#), [OUT_T_H \(0Eh\)](#) stored as two's complement data, left-justified in 12-bit mode and in [OUT_T \(26h\)](#) stored as two's complement data, left-justified in 8-bit mode.

Refer to [Table 5. Temperature sensor characteristics](#) for the conversion factor.

4 Application hints

Figure 6. LIS2DW12 electrical connections (top view)



The device core is supplied through the Vdd line while the I/O pads are supplied through the Vdd_IO line. Power supply decoupling capacitors (100 nF ceramic, 10 µF aluminum) should be placed as near as possible to pin 9 of the device (common design practice).

All the voltage and ground supplies must be present at the same time to have proper behavior of the IC (refer to [Figure 6. LIS2DW12 electrical connections \(top view\)](#)). It is possible to remove Vdd while maintaining Vdd_IO without blocking the communication bus, in this condition the measurement chain is powered off.

The functionality of the device and the measured acceleration data are selectable and accessible through the I²C or SPI interfaces. When using the I²C, CS must be tied high (i.e. connected to Vdd_IO).

The functions, the threshold and the timing of the two interrupt pins (INT1 and INT2) can be completely programmed by the user through the I²C/SPI interface.

Table 12. Internal pin status

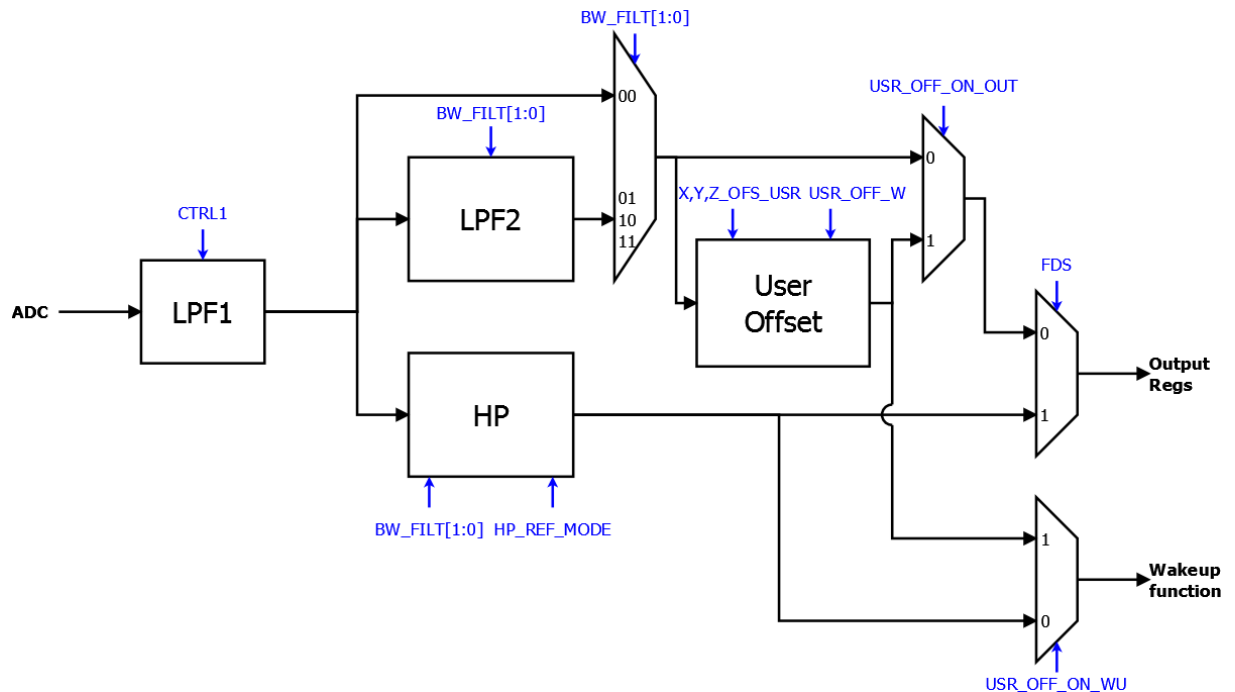
| Pin # | Name | Function | Pin status |
|-------|--------|---|---|
| 1 | SCL | I ² C serial clock (SCL) | Default: open drain |
| | SPC | SPI serial port clock (SPC) | |
| 2 | CS | Enable SPI | Default: input with internal pull-up ⁽¹⁾ |
| | | I ² C/SPI mode selection | |
| | | 1: SPI idle mode / I ² C communication enabled | |
| | | 0: SPI communication mode / I ² C disabled | |
| 3 | SDO | Serial data output (SDO) | Default: input with internal pull-up |
| | SA0 | I ² C less significant bit of the device address (SA0) | |
| 4 | SDA | I ² C serial data (SDA) | Default: (SDA) input open drain |
| | SDI | SPI serial data input (SDI) | |
| | SDO | 3-wire interface serial data output (SDO) | |
| 5 | NC | Internally not connected. Can be tied to VDD, VDDIO, or GND. | |
| 6 | GND | 0 V supply | |
| 7 | RES | Connect to GND | |
| 8 | GND | 0 V supply | |
| 9 | VDD | Power supply | |
| 10 | VDD_IO | Power supply for I/O pins | |
| 11 | INT2 | Interrupt pin 2. Clock input when selected in single data conversion on-demand. | Default: push-pull output forced to Gnd |
| 12 | INT1 | Interrupt pin 1 | Default: push-pull output forced to Gnd |

1. In order to disable the internal pull-up on the CS pin, write 1 to the CS_PU_DISC bit in CTRL2 (21h).

5 Digital main blocks

5.1 Block diagram of filters

Figure 7. Accelerometer chain



Referring to [Figure 7. Accelerometer chain](#), the first block is the low-pass filter 1 (LPF1) whose behavior is a function of the actual ODR and mode selected in [CTRL1 \(20h\)](#). The signal is then downsampled and can be either directly sent to the output registers or to the low-pass filter 2 (LPF2) or high-pass filter (HP) using the [BW_FILT\[1:0\]](#) bits and [FDS](#) bit in [CTRL6 \(25h\)](#).

In the low-pass path, it is possible to apply a user offset determined by the [X_OFS_USR \(3Ch\)](#), [Y_OFS_USR \(3Dh\)](#), [Z_OFS_USR \(3Eh\)](#) register values and the [USR_OFF_W](#) bit in [CTRL7 \(3Fh\)](#) and send the result to the output using the [USR_OFF_ON_OUT](#) bit in [CTRL7 \(3Fh\)](#).

In the high-pass path, it is possible to use the high-pass filter reference mode (HP) using the [HP_REF_MODE](#) bit in [CTRL7 \(3Fh\)](#).

5.2 Data stabilization time vs. ODR/device setting

Some data samples need to be discarded when changing the ODR in HP mode with ODR/2 bandwidth selection. The table below provides the number of samples to be discarded in order to obtain valid usable data.

Table 13. Number of samples to be discarded

| MODE[1:0] in CTRL1 (20h) | ODR [Hz] | BW_FILT[1:0] in CTRL6 (25h) | Samples to be discarded |
|-----------------------------|----------|--------------------------------|-------------------------|
| 00 | - | 00 | 0 |
| 01 | 12.5 | | 0 |
| | 25 | | 0 |
| | 50 | | 0 |
| | 100 | | 1 |
| | 200 | | 1 |
| | 400 | | 1 |
| | 800 | | 1 |
| | 1600 | | 2 |

5.3 FIFO

The LIS2DW12 embeds 32 slots of 14-bit data FIFO for each of the three output channels, X, Y, and Z of the acceleration data. This allows consistent power saving for the system, since the host processor does not need to continuously poll data from the sensor, but it can wake up only when needed and burst the significant data out from the FIFO.

The internal FIFO allows collecting 32 samples (14-bit size data) for each axis.

When the FIFO mode is other than bypass, reading the output registers (28h to 2Dh) returns the oldest FIFO sample set. In order to minimize communication between the master and slave, the address read may be automatically incremented by the device by setting the IF_ADD_INC bit of CTRL2 (21h) to 1. The device rolls back to 0x28 when register 0x2D is reached.

This buffer can work according to the following five different modes:

- Bypass mode
- FIFO mode
- Continuous-to-FIFO
- Bypass-to-continuous
- Continuous

Each mode is selected by the FMode[2:0] bits in the FIFO_CTRL (2Eh) register.

Programmable FIFO threshold is selected in FIFO_CTRL (2Eh). Status and FIFO overrun events are available in the FIFO_SAMPLES (2Fh) register and can be used to generate dedicated interrupts on the INT1 and INT2 pins using the CTRL4_INT1_PAD_CTRL (23h) and CTRL5_INT2_PAD_CTRL (24h) registers.

FIFO_SAMPLES (2Fh) (FIFO_FTH) goes to 1 when the number of unread samples FIFO_SAMPLES (2Fh) (Diff[5:0]) is greater than or equal to FTH[4:0] in FIFO_CTRL (2Eh).

If FTH[4:0] is equal to 0, FIFO_SAMPLES (2Fh) (FIFO_FTH) goes to 0.

FIFO_SAMPLES (2Fh) (FIFO_OVR) is equal to 1 if a FIFO slot is overwritten.

FIFO_SAMPLES (2Fh) (Diff[5:0]) contains stored data levels of unread samples. When Diff[5:0] is equal to 000000, FIFO is empty. When Diff[5:0] is equal to 100000, FIFO is full and the unread samples are 32.

To guarantee the correct acquisition of data during the switching into and out of FIFO, the first sample acquired must be discarded.

When the FIFO threshold status flag is 0 logic, FIFO filling is lower than the threshold level and when 1 logic, FIFO filling is equal to or higher than the threshold level.

5.3.1 Bypass mode

In bypass mode ([FIFO_CTRL \(2Eh\)](#) (FMode [2:0])= 000), the FIFO is not operational, no data is collected in FIFO memory, and it remains empty with the only actual sample available in the output registers.

Bypass mode is also used to reset the FIFO when in FIFO mode.

For each channel, only the first address is used. When new data is available, the old data is overwritten.

5.3.2 FIFO mode

In FIFO mode ([FIFO_CTRL \(2Eh\)](#)(FMode [2:0])= 001) data from the X, Y, and Z channels are stored in the FIFO until it is full, when 32 unread samples are stored in memory, data collecting is stopped.

To reset the FIFO content, bypass mode should be written in the [FIFO_CTRL \(2Eh\)](#) register, setting the FMODE [2:0] bits to 000. After this reset command, it is possible to restart FIFO mode, writing the value 001 in [FIFO_CTRL \(2Eh\)](#)(FMODE [2:0]).

The FIFO buffer can memorize 32 slots of X, Y, and Z data.

5.3.3 Continuous mode

Continuous mode ([FIFO_CTRL \(2Eh\)](#) (FMode[2:0] = 110) provides a continuous FIFO update: when 32 unread samples are stored in memory, as new data arrives the oldest data is discarded and overwritten by the newer.

A FIFO threshold flag [FIFO_SAMPLES \(2Fh\)](#) (FIFO_FTH) is asserted when the number of unread samples in FIFO is greater than or equal to ([FIFO_CTRL \(2Eh\)](#)FTH[4:0]).

It is possible to route [FIFO_SAMPLES \(2Fh\)](#)(FTH) to the INT1 pin by writing the INT1_FTH bit to 1 in register [CTRL4_INT1_PAD_CTRL \(23h\)](#) or to the INT2 pin by writing the INT2_FTH bit to 1 in register [CTRL5_INT2_PAD_CTRL \(24h\)](#).

If an overrun occurs, the oldest sample in FIFO is overwritten and the FIFO_OVR flag in [FIFO_SAMPLES \(2Fh\)](#) is asserted.

In order to empty the FIFO before it is full, it is also possible to pull from FIFO the number of unread samples available in [FIFO_SAMPLES \(2Fh\)](#) (Diff[5:0]).

5.3.4 Continuous-to-FIFO mode

In continuous-to-FIFO mode `FIFO_CTRL (2Eh)(FMode[2:0] = 011)`, FIFO operates in continuous mode and FIFO mode starts upon an internal trigger event. When the FIFO is full, data collecting is stopped. The trigger could be a single or double tap, wake-up, free-fall, 6D interrupt, or any combination of these events, but every interrupt has to be routed to the corresponding pad to be used as a trigger.

Figure 8. Continuous-to-FIFO mode

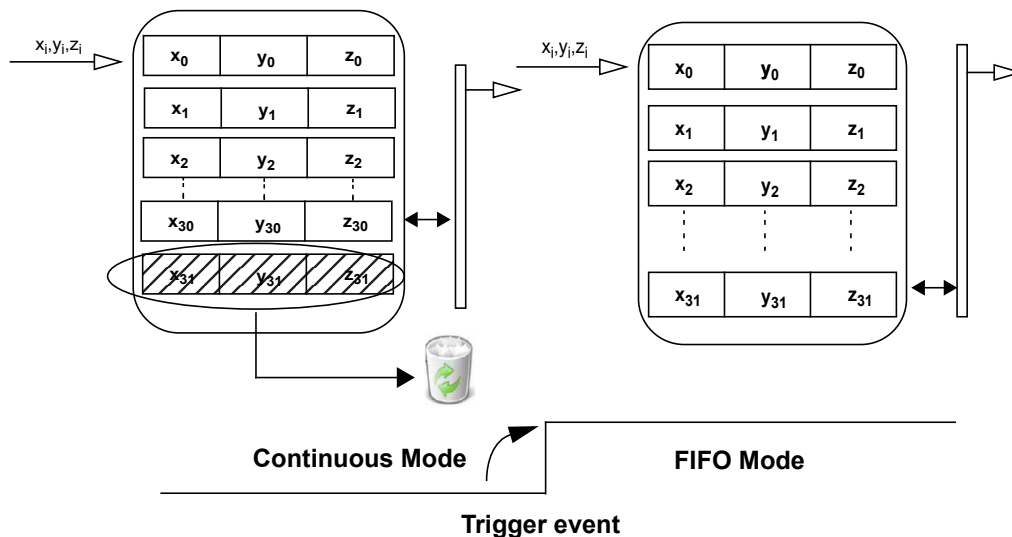
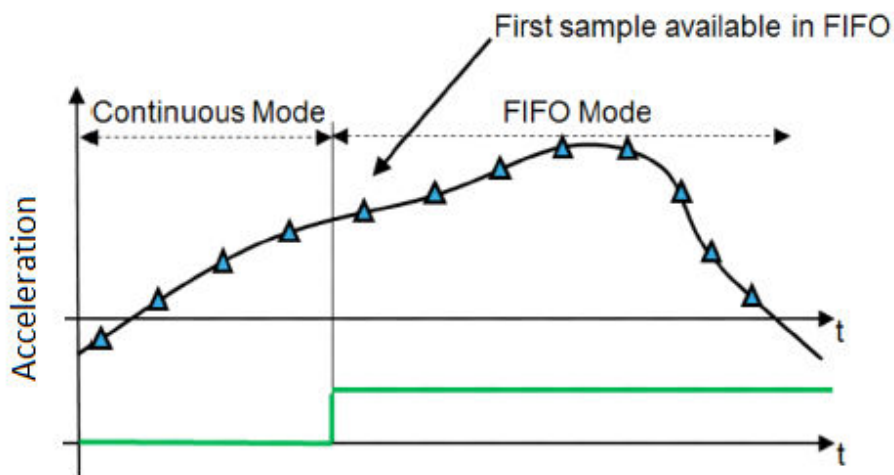


Figure 9. Trigger event to FIFO for continuous-to-FIFO mode



5.3.5 Bypass-to-continuous mode

In bypass-to-continuous mode (FIFO_CTRL (2Eh)(FMode[2:0] = 100), data measurement storage inside FIFO starts in continuous mode upon an internal trigger event, then the sample that follows the trigger is available in FIFO. The trigger could be a single or double tap, wake-up, free-fall, 6D interrupt, or any combination of these events, but every interrupt has to be routed to the corresponding pad to be used as a trigger.

Figure 10. Bypass-to-continuous mode

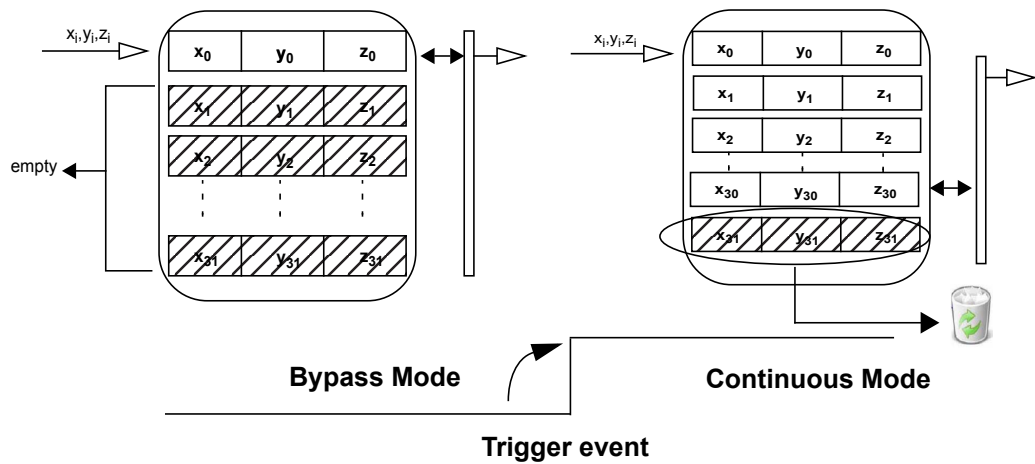
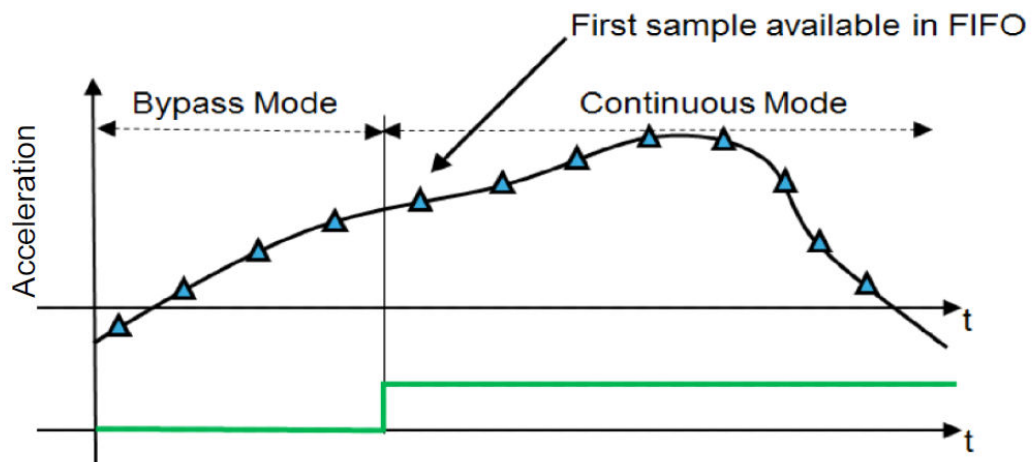


Figure 11. Trigger event to FIFO for bypass-to-continuous mode



6 Digital interfaces

The registers embedded inside the LIS2DW12 may be accessed through both the I²C and SPI serial interfaces. The latter may be software configured to operate either in 3-wire or 4-wire interface mode.

The serial interfaces are mapped to the same pins. To select/exploit the I²C interface, the CS line must be tied high (that is, connected to Vdd_IO).

Table 14. Serial interface pin description

| Pin name | Pin description |
|----------|--|
| CS | Enable SPI I ² C/SPI mode selection (1: SPI idle mode / I ² C communication enabled; 0: SPI communication mode / I ² C disabled) |
| SCL | I ² C serial clock (SCL) |
| SPC | SPI serial port clock (SPC) |
| SDA | I ² C serial data (SDA) |
| SDI | SPI serial data input (SDI) |
| SDO | 3-wire interface serial data output (SDO) |
| SA0 | I ² C address selection (SA0) |
| SDO | SPI serial data output (SDO) |

6.1 I²C serial interface

The LIS2DW12 I²C is a bus slave. The I²C is employed to write data into registers whose content can also be read back.

The relevant I²C terminology is given in the table below.

Table 15. I²C terminology

| Term | Description |
|-------------|--|
| Transmitter | The device that sends data to the bus |
| Receiver | The device that receives data from the bus |
| Master | The device that initiates a transfer, generates clock signals, and terminates a transfer |
| Slave | The device addressed by the master |

There are two signals associated with the I²C bus: the serial clock line (SCL) and the serial data line (SDA). The latter is a bidirectional line used for sending and receiving the data to/from the interface. Both the lines must be connected to Vdd_IO through an external pull-up resistor. When the bus is free, both the lines are high.

The I²C interface supports fast mode (400 kHz) I²C standards as well as normal mode.

In order to disable the I²C block, CTRL2 (21h) (I2C_DISABLE) = 1 must be set.

6.1.1 I²C operation

The transaction on the bus is started through a start (ST) signal. A start condition is defined as a high to low transition on the data line while the SCL line is held high. After this has been transmitted by the master, the bus is considered busy. The next byte of data transmitted after the start condition contains the address of the slave in the first 7 bits and the eighth bit tells whether the master is receiving data from the slave or transmitting data to the slave. When an address is sent, each device in the system compares the first seven bits after a start condition with its address. If they match, the device considers itself addressed by the master.

The slave address (SAD) associated to the LIS2DW12 is 001100xb where the x bit is modified by the SA0/SDO pin in order to modify the device address. If the SA0/SDO pin is connected to the supply voltage, the address is 0011001b, otherwise if the SA0/SDO pin is connected to ground, the address is 0011000b. This solution permits to connect and address two different accelerometers to the same I²C lines.

Data transfer with acknowledge is mandatory. The transmitter must release the SDA line during the acknowledge pulse. The receiver must then pull the data line low so that it remains stable low during the high period of the acknowledge clock pulse. A receiver that has been addressed is obliged to generate an acknowledge after each byte of data received.

The I²C embedded inside the LIS2DW12 behaves like a slave device and the following protocol must be adhered to. After the start condition (ST), a slave address is sent. Once a slave acknowledge (SAK) has been returned, an 8-bit subaddress (SUB) is transmitted: the 7 LSB represents the actual register address while the CTRL2 (21h) (IF_ADD_INC) bit defines the address increment.

The slave address is completed with a read/write bit. If the bit is 1 (read), a repeated start (SR) condition must be issued after the two subaddress bytes. If the bit is 0 (write) the master transmits to the slave with direction unchanged. Table 16 explains how the SAD+read/write bit pattern is composed, listing all the possible configurations.

Table 16. SAD+read/write patterns

| Command | SAD[6:1] | SAD[0] = SA0 | R/W | SAD+R/W |
|---------|----------|--------------|-----|----------------|
| Read | 001100 | 0 | 1 | 00110001 (31h) |
| Write | 001100 | 0 | 0 | 00110000 (30h) |
| Read | 001100 | 1 | 1 | 00110011 (33h) |
| Write | 001100 | 1 | 0 | 00110010 (32h) |

Table 17. Transfer when master is writing one byte to slave

| | | | | | | | | |
|--------|----|---------|-----|-----|-----|------|-----|----|
| Master | ST | SAD + W | | SUB | | DATA | | SP |
| Slave | | | SAK | | SAK | | SAK | |

Table 18. Transfer when master is writing multiple bytes to slave

| | | | | | | | | | | |
|--------|----|---------|-----|-----|-----|------|-----|------|-----|----|
| Master | ST | SAD + W | | SUB | | DATA | | DATA | | SP |
| Slave | | | SAK | | SAK | | SAK | | SAK | |

Table 19. Transfer when master is receiving (reading) one byte of data from slave

| | | | | | | | | | | | |
|--------|----|---------|-----|-----|-----|----|---------|-----|------|------|----|
| Master | ST | SAD + W | | SUB | | SR | SAD + R | | | NMAK | SP |
| Slave | | | SAK | | SAK | | | SAK | DATA | | |

Table 20. Transfer when master is receiving (reading) multiple bytes of data from slave

| | | | | | | | | | | | | | | | |
|--------|----|-------|-----|-----|-----|----|-------|-----|------|-----|------|-----|------|------|----|
| Master | ST | SAD+W | | SUB | | SR | SAD+R | | | MAK | | MAK | | NMAK | SP |
| Slave | | | SAK | | SAK | | | SAK | DATA | | DATA | | DATA | | |

Data are transmitted in byte format (DATA). Each data transfer contains 8 bits. The number of bytes transferred per transfer is unlimited. Data is transferred with the most significant bit (MSb) first. If a receiver cannot receive another complete byte of data until it has performed some other function, it can hold the clock line, SCL low to force the transmitter into a wait state. Data transfer only continues when the receiver is ready for another byte and releases the data line. If a slave receiver does not acknowledge the slave address (that is, it is not able to receive because it is performing some real-time function) the data line must be left high by the slave. The master can then abort the transfer. A low to high transition on the SDA line while the SCL line is high is defined as a stop condition. Each data transfer must be terminated by the generation of a stop (SP) condition.

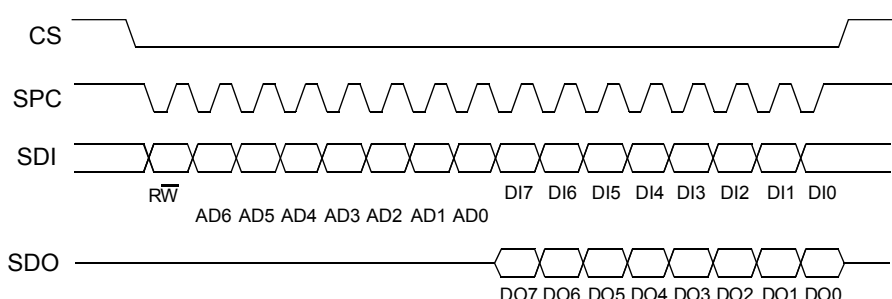
In the presented communication format MAK is master acknowledge and NMAK is no master acknowledge.

6.2 SPI bus interface

The LIS2DW12 SPI is a bus slave. The SPI allows writing to and reading from the registers of the device.

The serial interface interacts with the application using four wires: **CS**, **SPC**, **SDI**, and **SDO**.

Figure 12. Read and write protocol



CS enables the serial port and it is controlled by the SPI master. It goes low at the start of the transmission and goes back high at the end. **SPC** is the serial port clock and it is controlled by the SPI master. It is stopped high when **CS** is high (no transmission). **SDI** and **SDO** are respectively the serial port data input and output. Those lines are driven at the falling edge of **SPC** and should be captured at the rising edge of **SPC**.

Both the read register and write register commands are completed in 16 clock pulses or in multiples of 8 in case of multiple read/write bytes. Bit duration is the time between two falling edges of **SPC**. The first bit (bit 0) starts at the first falling edge of **SPC** after the falling edge of **CS** while the last bit (bit 15, bit 23, ...) starts at the last falling edge of **SPC** just before the rising edge of **CS**.

bit 0: \overline{RW} bit. When 0, the data DI(7:0) is written into the device. When 1, the data DO(7:0) from the device is read. In the latter case, the chip drives **SDO** at the start of bit 8.

bit 1-7: address AD(6:0). This is the address field of the indexed register.

bit 8-15: data DI(7:0) (write mode). This is the data that is written into the device (MSb first).

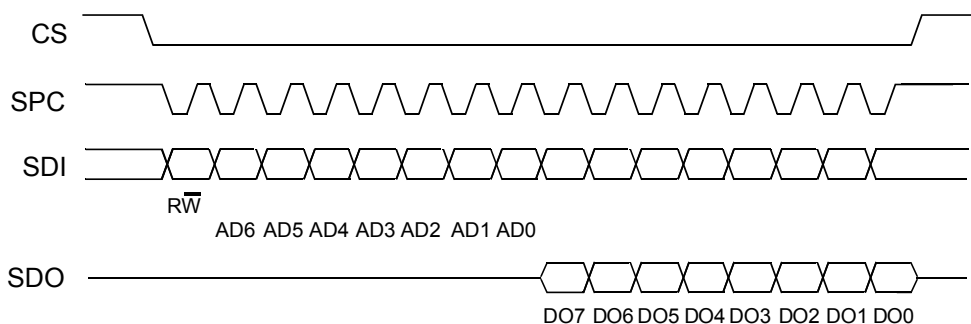
bit 8-15: data DO(7:0) (read mode). This is the data that is read from the device (MSb first).

In multiple read/write commands, additional blocks of 8 clock periods are added. When the [CTRL2 \(21h\)](#) (IF_ADD_INC) bit is 0, the address used to read/write data remains the same for every block. When the [CTRL2 \(21h\)](#) (IF_ADD_INC) bit is 1, the address used to read/write data is increased at every block.

The function and the behavior of **SDI** and **SDO** remain unchanged.

6.2.1 SPI read

Figure 13. SPI read protocol



The SPI read command is performed with 16 clock pulses. A multiple byte read command is performed by adding blocks of 8 clock pulses to the previous one.

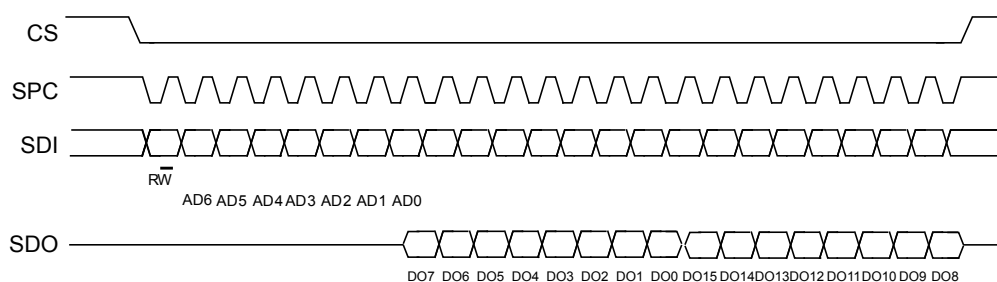
bit 0: READ bit. The value is 1.

bit 1-7: address AD(6:0). This is the address field of the indexed register.

bit 8-15: data DO(7:0) (read mode). This is the data that is read from the device (MSb first).

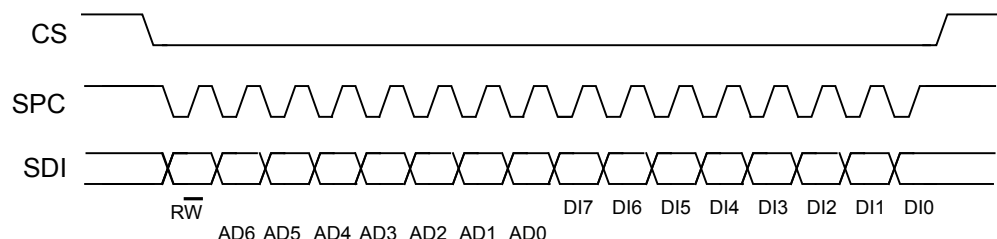
bit 16-... : data DO(...-8). Additional data in multiple byte reads.

Figure 14. Multiple byte SPI read protocol (2-byte example)



6.2.2 SPI write

Figure 15. SPI write protocol



The SPI write command is performed with 16 clock pulses. A multiple byte write command is performed by adding blocks of 8 clock pulses to the previous one.

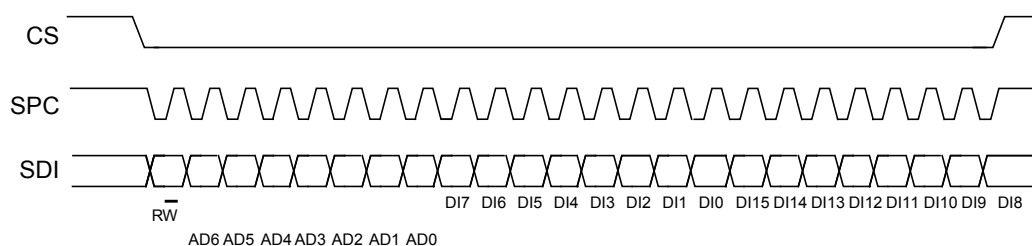
bit 0: WRITE bit. The value is 0.

bit 1 -7: address AD(6:0). This is the address field of the indexed register.

bit 8-15: data DI(7:0) (write mode). This is the data that is written inside the device (MSb first).

bit 16-... : data DI(...-8). Additional data in multiple byte writes.

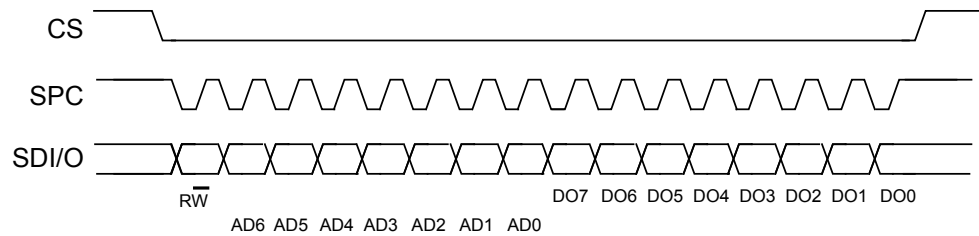
Figure 16. Multiple byte SPI write protocol (2-byte example)



6.2.3 SPI read in 3-wire mode

3-wire mode is entered by setting the **CTRL2 (21h)** (SIM) bit equal to 1 (SPI serial interface mode selection).

Figure 17. SPI read protocol in 3-wire mode



The SPI read command is performed with 16 clock pulses:

bit 0: READ bit. The value is 1.

bit 1-7: address AD(6:0). This is the address field of the indexed register.

bit 8-15: data DO(7:0) (read mode). This is the data that is read from the device (MSb first).

A multiple read command is also available in 3-wire mode.

7 Register mapping

The table given below provides a list of the 8-bit registers embedded in the device and the corresponding addresses.

Table 21. Register map

| Name | Type ⁽¹⁾ | Register address | | Default | Comment |
|---------------------|---------------------|------------------|----------|----------|--|
| | | Hex | Binary | | |
| OUT_T_L | R | 0D | 00001101 | 00000000 | Temp sensor output |
| OUT_T_H | R | 0E | 00001110 | 00000000 | |
| WHO_AM_I | R | 0F | 00001111 | 01000100 | Who am I ID |
| RESERVED | - | 10-1F | | - | RESERVED |
| CTRL1 | R/W | 20 | 00100000 | 00000000 | Control registers |
| CTRL2 | R/W | 21 | 00100001 | 00000100 | |
| CTRL3 | R/W | 22 | 00100010 | 00000000 | |
| CTRL4_INT1_PAD_CTRL | R/W | 23 | 00100011 | 00000000 | |
| CTRL5_INT2_PAD_CTRL | R/W | 24 | 00100100 | 00000000 | |
| CTRL6 | R/W | 25 | 00100101 | 00000000 | |
| OUT_T | R | 26 | 00100110 | 00000000 | Temp sensor output |
| STATUS | R | 27 | 00100111 | 00000000 | Status data register |
| OUT_X_L | R | 28 | 00101000 | 00000000 | Output registers |
| OUT_X_H | R | 29 | 00101001 | 00000000 | |
| OUT_Y_L | R | 2A | 00101010 | 00000000 | |
| OUT_Y_H | R | 2B | 00101011 | 00000000 | |
| OUT_Z_L | R | 2C | 00101100 | 00000000 | |
| OUT_Z_H | R | 2D | 00101101 | 00000000 | |
| FIFO_CTRL | R/W | 2E | 00101110 | 00000000 | FIFO control register |
| FIFO_SAMPLES | R | 2F | 00101111 | 00000000 | Unread samples stored in FIFO |
| TAP_THS_X | R/W | 30 | 00110000 | 00000000 | Tap thresholds |
| TAP_THS_Y | R/W | 31 | 00110001 | 00000000 | |
| TAP_THS_Z | R/W | 32 | 00110010 | 00000000 | |
| INT_DUR | R/W | 33 | 00110011 | 00000000 | Interrupt duration |
| WAKE_UP_THS | R/W | 34 | 00110100 | 00000000 | Tap/double-tap selection, inactivity enable, wake-up threshold |
| WAKE_UP_DUR | R/W | 35 | 00110101 | 00000000 | Wake-up duration |
| FREE_FALL | R/W | 36 | 00110110 | 00000000 | Free-fall configuration |
| STATUS_DUP | R | 37 | 00110111 | 00000000 | Status register |
| WAKE_UP_SRC | R | 38 | 00111000 | 00000000 | Wake-up source |
| TAP_SRC | R | 39 | 00111001 | 00000000 | Tap source |
| SIXD_SRC | R | 3A | 00111010 | 00000000 | 6D source |
| ALL_INT_SRC | R | 3B | 00111011 | 00000000 | |
| X_OFS_USR | R/W | 3C | 00111100 | 00000000 | |

| Name | Type ⁽¹⁾ | Register address | | Default | Comment |
|-----------|---------------------|------------------|----------|----------|---------|
| | | Hex | Binary | | |
| Y_OFS_USR | R/W | 3D | 00111110 | 00000000 | |
| Z_OFS_USR | R/W | 3E | 00000100 | 00000000 | |
| CTRL7 | R/W | 3F | 00000100 | 00000000 | |

1. R = read-only register, R/W = readable/writable register

Registers marked as Reserved must not be changed. Writing to those registers may cause permanent damage to the device.

The content of the registers that are loaded at boot should not be changed. They contain the factory calibration values. Their content is automatically restored when the device is powered up.

8 Register description

8.1 OUT_T_L (0Dh)

Temperature output register in 12-bit resolution (R)

Table 22. OUT_T_L register

| | | | | | | | |
|-------|-------|-------|-------|---|---|---|---|
| TEMP3 | TEMP2 | TEMP1 | TEMP0 | 0 | 0 | 0 | 0 |
|-------|-------|-------|-------|---|---|---|---|

Table 23. OUT_T_L register description

| | |
|-----------|---|
| TEMP[3:0] | The 8 least significant bits of the temperature sensor output. 0 LSB = 25°C. Sensitivity = 16 LSB/°C. Together with OUT_T_H (0Eh), it forms the output value expressed as a 16-bit word in two's complement. |
|-----------|---|

8.2 OUT_T_H (0Eh)

Temperature output register in 12-bit resolution (R)

Table 24. OUT_T_H register

| | | | | | | | |
|--------|--------|-------|-------|-------|-------|-------|-------|
| TEMP11 | TEMP10 | TEMP9 | TEMP8 | TEMP7 | TEMP6 | TEMP5 | TEMP4 |
|--------|--------|-------|-------|-------|-------|-------|-------|

Table 25. OUT_T_H register description

| | |
|------------|---|
| TEMP[11:4] | The 8 most significant bits of the temperature sensor output. 0 LSB = 25°C. Sensitivity = 16 LSB/°C. Together with OUT_T_L (0Dh), it forms the output value expressed as a 16-bit word in two's complement |
|------------|---|

8.3 WHO_AM_I (0Fh)

Who_AM_I register (R). This register is a read-only register. Its value is fixed at 44h.

Table 26. WHO_AM_I register default values

| | | | | | | | |
|---|---|---|---|---|---|---|---|
| 0 | 1 | 0 | 0 | 0 | 1 | 0 | 0 |
|---|---|---|---|---|---|---|---|

8.4

CTRL1 (20h)

Control register 1 (R/W)

Table 27. Control register 1

| | | | | | | | |
|------|------|------|------|-------|-------|----------|----------|
| ODR3 | ODR2 | ODR1 | ODR0 | MODE1 | MODE0 | LP_MODE1 | LP_MODE0 |
|------|------|------|------|-------|-------|----------|----------|

Table 28. Control register 1 description

| | |
|--------------|---|
| ODR[3:0] | Output data rate and mode selection (see Table 29. Data rate configuration) |
| MODE[1:0] | Mode selection (see Table 30. Mode selection) |
| LP_MODE[1:0] | Low-power mode selection (see Table 31. Low-power mode selection) |

ODR[3:0] is used to set the power mode and ODR selection. The following table lists the bit settings for power-down mode and each available frequency.

Table 29. Data rate configuration

| ODR[3:0] | Power mode / data rate configuration |
|----------|---|
| 0000 | Power-down |
| 0001 | High-performance / low-power mode 12.5 / 1.6 Hz |
| 0010 | High-performance / low-power mode 12.5 Hz |
| 0011 | High-performance / low-power mode 25 Hz |
| 0100 | High-performance / low-power mode 50 Hz |
| 0101 | High-performance / low-power mode 100 Hz |
| 0110 | High-performance / low-power mode 200 Hz |
| 0111 | High-performance / low-power mode 400 / 200 Hz |
| 1000 | High-performance / low-power mode 800 / 200 Hz |
| 1001 | High-performance / low-power mode 1600 / 200 Hz |

Table 30. Mode selection

| MODE[1:0] | Mode and resolution |
|-----------|--|
| 00 | Low-power mode (12/14-bit resolution) |
| 01 | High-performance mode (14-bit resolution) |
| 10 | Single data conversion on-demand mode (12/14-bit resolution) |
| 11 | - |

Table 31. Low-power mode selection

| LP_MODE[1:0] | Power mode and resolution |
|--------------|--------------------------------------|
| 00 | Low-power mode 1 (12-bit resolution) |
| 01 | Low-power mode 2 (14-bit resolution) |
| 10 | Low-power mode 3 (14-bit resolution) |
| 11 | Low-power mode 4 (14-bit resolution) |

8.5

CTRL2 (21h)

Control register 2 (R/W)

Table 32. Control register 2

| BOOT | SOFT_RESET | 0 ⁽¹⁾ | CS_PU_DISC | BDU | IF_ADD_INC | I2C_DISABLE | SIM |
|------|------------|------------------|------------|-----|------------|-------------|-----|
|------|------------|------------------|------------|-----|------------|-------------|-----|

1. This bit must be set to 0 for the correct operation of the device.

| | |
|-------------|---|
| BOOT | <p>Boot enables retrieving the correct trimming parameters from nonvolatile memory into registers where trimming parameters are stored.</p> <p>Once the operation is over, this bit automatically returns to 0.</p> <p>Default value: 0 (0: disabled; 1: enabled)</p> |
| SOFT_RESET | <p>Soft reset acts as reset for all control registers, then goes to 0.</p> <p>Default value: 0 (0: disabled; 1: enabled)</p> |
| CS_PU_DISC | <p>Disconnect CS pull-up. Default value: 0</p> <p>(0: pull-up connected to CS pin; 1: pull-up disconnected to CS pin)</p> |
| BDU | <p>Block data update. Default value: 0</p> <p>(0: continuous update; 1: output registers not updated until MSB and LSB read)</p> |
| IF_ADD_INC | <p>Register address automatically incremented during multiple byte access with a serial interface (I²C or SPI). Default value: 1</p> <p>(0: disabled; 1: enabled)</p> |
| I2C_DISABLE | <p>Disable I²C communication protocol. Default value: 0</p> <p>(0: SPI and I²C interfaces enabled; 1: I²C mode disabled)</p> |
| SIM | <p>SPI serial interface mode selection. Default value: 0</p> <p>(0: 4-wire interface; 1: 3-wire interface)</p> |

The BDU bit is used to inhibit the update of the output registers until both upper and lower register parts are read. In default mode (BDU = 0) the output register values are updated continuously. When the BDU is activated (BDU = 1), the content of the output registers is not updated until both MSB and LSB are read which avoids reading values related to different sample times.

8.6

CTRL3 (22h)

Control register 3 (R/W)

Table 33. Control register 3

| | | | | | | | |
|-----|-----|-------|-----|-----------|---|--------------|------------|
| ST2 | ST1 | PP_OD | LIR | H_LACTIVE | 0 | SLP_MODE_SEL | SLP_MODE_1 |
|-----|-----|-------|-----|-----------|---|--------------|------------|

Table 34. Control register 3 description

| | |
|--------------|---|
| ST[2:1] | Enables self-test. Default value: 00 (00: self-test disabled; other: see Table 35. Self-test mode selection) |
| PP_OD | Push-pull/open-drain selection on interrupt pad. Default value: 0 (0: push-pull; 1: open-drain) |
| LIR | Latched interrupt. Switches between latched (1 logic) and pulsed (0 logic) mode for function source signals and interrupts routed to pins (wake-up, single/double-tap). Default value: 0 (0: interrupt request not latched; 1: interrupt request latched) |
| H_LACTIVE | Interrupt active high, low. Default value: 0 (0: active high; 1: active low) |
| SLP_MODE_SEL | Single data conversion on demand mode selection: (0: enabled with external trigger on INT2; 1: enabled by I ² C/SPI writing SLP_MODE_1 to 1) |
| SLP_MODE_1 | Single data conversion on-demand mode enable. When SLP_MODE_SEL = 1 and this bit is set to 1 logic, single data conversion on-demand mode starts. When accelerometer data are available in the registers, this bit is set to 0 automatically and the device is ready for another triggered session. |

Table 35. Self-test mode selection

| ST2 | ST1 | Self-test mode |
|-----|-----|-------------------------|
| 0 | 0 | Normal mode |
| 0 | 1 | Positive sign self-test |
| 1 | 0 | Negative sign self-test |
| 1 | 1 | - |

8.7 CTRL4_INT1_PAD_CTRL (23h)

Control register 4 (R/W)

Table 36. Control register 4

| | | | | | | | |
|---------|-----------------|---------|---------|----------|------------|----------|-----------|
| INT1_6D | INT1_SINGLE_TAP | INT1_WU | INT1_FF | INT1_TAP | INT1_DIFF5 | INT1_FTH | INT1_DRDY |
|---------|-----------------|---------|---------|----------|------------|----------|-----------|

Table 37. Control register 4 description

| | |
|-----------------|---|
| INT1_6D | 6D recognition is routed to INT1 pad. Default: 0 (0: disabled; 1: enabled) |
| INT1_SINGLE_TAP | Single-tap recognition is routed to INT1 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT1_WU | Wake-up recognition is routed to INT1 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT1_FF | Free-fall recognition is routed to INT1 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT1_TAP | Double-tap recognition is routed to INT1 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT1_DIFF5 | FIFO full recognition is routed to INT1 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT1_FTH | FIFO threshold interrupt is routed to INT1 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT1_DRDY | Data-ready is routed to INT1 pad. Default value: 0 (0: disabled; 1: enabled) |

8.8 CTRL5_INT2_PAD_CTRL (24h)

Control register 5 (R/W)

Table 38. Control register 5

| | | | | | | | |
|------------------|----------------|-----------|-------------|----------|------------|----------|-----------|
| INT2_SLEEP_STATE | INT2_SLEEP_CHG | INT2_BOOT | INT2_DRDY_T | INT2_OVR | INT2_DIFF5 | INT2_FTH | INT2_DRDY |
|------------------|----------------|-----------|-------------|----------|------------|----------|-----------|

Table 39. Control register 5 description

| | |
|------------------|---|
| INT2_SLEEP_STATE | Enables routing SLEEP_STATE to INT2 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT2_SLEEP_CHG | Sleep change status routed to INT2 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT2_BOOT | Boot state routed to INT2 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT2_DRDY_T | Temperature data-ready is routed to INT2. Default value: 0 (0: disabled; 1: enabled) |
| INT2_OVR | FIFO overrun interrupt is routed to INT2 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT2_DIFF5 | FIFO full recognition is routed to INT2 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT2_FTH | FIFO threshold interrupt is routed to INT2 pad. Default value: 0 (0: disabled; 1: enabled) |
| INT2_DRDY | Data-ready is routed to INT2 pad. Default value: 0 (0: disabled; 1: enabled) |

8.9

CTRL6 (25h)

Control register 6 (R/W)

Table 40. Control register 6

| | | | | | | | |
|----------|----------|-----|-----|-----|-----------|---|---|
| BW_FILT1 | BW_FILT0 | FS1 | FS0 | FDS | LOW_NOISE | 0 | 0 |
|----------|----------|-----|-----|-----|-----------|---|---|

| | |
|--------------|--|
| BW_FILT[1:0] | Bandwidth selection (see Table 41. Digital filtering cutoff selection) |
| FS[1:0] | Full-scale selection (see Table 42. Full-scale selection) |
| FDS | Filtered data type selection. Default value: 0 (0: low-pass filter path selected; 1: high-pass filter path selected) |
| LOW_NOISE | Low-noise configuration. (0: disabled; 1: enabled) |

Table 41. Digital filtering cutoff selection

| BW_FILT[1:0] | Bandwidth selection |
|--------------|---|
| 00 | ODR/2 (up to ODR = 800 Hz, 400 Hz when ODR = 1600 Hz) |
| 01 | ODR/4 (HP/LP) |
| 10 | ODR/10 (HP/LP) |
| 11 | ODR/20 (HP/LP) |

Table 42. Full-scale selection

| FS[1:0] | Full-scale selection |
|---------|----------------------|
| 00 | $\pm 2\ g$ |
| 01 | $\pm 4\ g$ |
| 10 | $\pm 8\ g$ |
| 11 | $\pm 16\ g$ |

8.10 OUT_T (26h)

Temperature output register in 8-bit resolution (R)

Table 43. OUT_T register

| TEMP7 | TEMP6 | TEMP5 | TEMP4 | TEMP3 | TEMP2 | TEMP1 | TEMP0 |
|-------|-------|-------|-------|-------|-------|-------|-------|
|-------|-------|-------|-------|-------|-------|-------|-------|

Table 44. OUT_T register description

| | |
|-----------|--|
| TEMP[7:0] | <p>Temperature sensor output data.</p> <p>The value is expressed as two's complement sign. Sensitivity = 1°C/LSB</p> <p>0 LSB represents T = 25°C ambient.</p> |
|-----------|--|

8.11 STATUS (27h)

Status register (R)

Table 45. STATUS register

| FIFO_THS | WU_IA | SLEEP_STATE | DOUBLE_TAP | SINGLE_TAP | 6D_IA | FF_IA | DRDY |
|----------|-------|-------------|------------|------------|-------|-------|------|
|----------|-------|-------------|------------|------------|-------|-------|------|

Table 46. STATUS register description

| | |
|-------------|---|
| FIFO_THS | <p>FIFO threshold status flag</p> <p>(0: FIFO filling is lower than threshold level; 1: FIFO filling is equal to or higher than the threshold level.)</p> |
| WU_IA | <p>Wake-up event detection status</p> <p>(0: wake-up event not detected; 1: wake-up event detected)</p> |
| SLEEP_STATE | <p>Sleep event status.</p> <p>(0: sleep event not detected; 1: sleep event detected)</p> |
| DOUBLE_TAP | <p>Double-tap event status</p> <p>(0: double-tap event not detected; 1: double-tap event detected)</p> |
| SINGLE_TAP | <p>Single-tap event status</p> <p>(0: single-tap event not detected; 1: single-tap event detected)</p> |
| 6D_IA | <p>Source of change in position portrait/landscape/face-up/face-down</p> <p>(0: no event detected; 1: a change in position detected)</p> |
| FF_IA | <p>Free-fall event detection status</p> <p>(0: free-fall event not detected; 1: free-fall event detected)</p> |
| DRDY | <p>Data-ready status</p> <p>(0: not ready; 1: X-, Y- and Z-axis new data available)</p> |

8.12 OUT_X_L (28h)

X-axis LSB output register (R)

Table 47. OUT_X_L register

| | | | | | | | |
|------|------|------|------|---------------------|---------------------|---|---|
| X_L7 | X_L6 | X_L5 | X_L4 | X_L3 ⁽¹⁾ | X_L2 ⁽¹⁾ | 0 | 0 |
|------|------|------|------|---------------------|---------------------|---|---|

1. If low-power mode 1 is enabled, this bit is set to 0.

The 8 least significant bits of linear acceleration sensor X-axis output. Together with the OUT_X_H (29h) register, it forms the output value expressed as a 16-bit word in two's complement.

8.13 OUT_X_H (29h)

X-axis MSB output register (R)

Table 48. OUT_X_H register

| | | | | | | | |
|------|------|------|------|------|------|------|------|
| X_H7 | X_H6 | X_H5 | X_H4 | X_H3 | X_H2 | X_H1 | X_H0 |
|------|------|------|------|------|------|------|------|

The 8 most significant bits of linear acceleration sensor X-axis output. Together with the OUT_X_L (28h) register, it forms the output value expressed as a 16-bit word in two's complement.

8.14 OUT_Y_L (2Ah)

Y-axis LSB output register (R)

Table 49. OUT_Y_L register

| | | | | | | | |
|------|------|------|------|---------------------|---------------------|---|---|
| Y_L7 | Y_L6 | Y_L5 | Y_L4 | Y_L3 ⁽¹⁾ | Y_L2 ⁽¹⁾ | 0 | 0 |
|------|------|------|------|---------------------|---------------------|---|---|

1. If low-power mode 1 is enabled, this bit is set to 0.

The 8 least significant bits of linear acceleration sensor Y-axis output. Together with the OUT_Y_H (2Bh) register, it forms the output value expressed as a 16-bit word in two's complement.

8.15 OUT_Y_H (2Bh)

Y-axis MSB output register (R)

Table 50. OUT_Y_H register

| | | | | | | | |
|------|------|------|------|------|------|------|------|
| Y_H7 | Y_H6 | Y_H5 | Y_H4 | Y_H3 | Y_H2 | Y_H1 | Y_H0 |
|------|------|------|------|------|------|------|------|

The 8 most significant bits of linear acceleration sensor Y-axis output. Together with the OUT_Y_L (2Ah) register, it forms the output value expressed as a 16-bit word in two's complement.

8.16 OUT_Z_L (2Ch)

Z-axis LSB output register (R)

Table 51. OUT_Z_L register

| Z_L7 | Z_L6 | Z_L5 | Z_L4 | Z_L3 ⁽¹⁾ | Z_L2 ⁽¹⁾ | 0 | 0 |
|------|------|------|------|---------------------|---------------------|---|---|
|------|------|------|------|---------------------|---------------------|---|---|

1. If low-power mode 1 is enabled, this bit is set to 0.

The 8 least significant bits of linear acceleration sensor Z-axis output. Together with the [OUT_Z_H \(2Dh\)](#) register, it forms the output value expressed as a 16-bit word in two's complement.

8.17 OUT_Z_H (2Dh)

Z-axis MSB output register (R)

Table 52. OUT_Z_H register

| Z_H7 | Z_H6 | Z_H5 | Z_H4 | Z_H3 | Z_H2 | Z_H1 | Z_H0 |
|------|------|------|------|------|------|------|------|
|------|------|------|------|------|------|------|------|

The 8 most significant bits of linear acceleration sensor Z-axis output. Together with the [OUT_Z_L \(2Ch\)](#) register, it forms the output value expressed as a 16-bit word in two's complement.

8.18 FIFO_CTRL (2Eh)

FIFO control register (R/W)

Table 53. FIFO_CTRL register

| FMode2 | FMode1 | FMode0 | FTH4 | FTH3 | FTH2 | FTH1 | FTH0 |
|--------|--------|--------|------|------|------|------|------|
|--------|--------|--------|------|------|------|------|------|

Table 54. FIFO_CTRL register description

| | |
|------------|---|
| FMode[2:0] | FIFO mode selection bits. Default: 000. For further details, refer to Table 55. FIFO mode selection . |
| FTH[4:0] | FIFO threshold level setting |

Table 55. FIFO mode selection

| FMode[2:0] | Mode description |
|------------|---|
| 000 | Bypass mode: FIFO turned off |
| 001 | FIFO mode: stops collecting data when FIFO is full |
| 010 | Reserved |
| 011 | Continuous-to-FIFO: stream mode until trigger is deasserted, then FIFO mode |
| 100 | Bypass-to-continuous: bypass mode until trigger is deasserted, then FIFO mode |
| 101 | Reserved |
| 110 | Continuous mode: If the FIFO is full, the new sample overwrites the older sample. |
| 111 | Reserved |

8.19 FIFO_SAMPLES (2Fh)

FIFO_SAMPLES control register (R)

Table 56. FIFO_SAMPLES register

| | | | | | | | |
|----------|----------|-------|-------|-------|-------|-------|-------|
| FIFO_FTH | FIFO_OVR | Diff5 | Diff4 | Diff3 | Diff2 | Diff1 | Diff0 |
|----------|----------|-------|-------|-------|-------|-------|-------|

Table 57. FIFO_SAMPLES register description

| | |
|-----------|---|
| FIFO_FTH | FIFO threshold status flag (0: FIFO filling is lower than threshold level; 1: FIFO filling is equal to or higher than the threshold level.) |
| FIFO_OVR | FIFO overrun status (0: FIFO is not completely filled; 1: FIFO is completely filled and at least one sample has been overwritten) |
| Diff[5:0] | Represents the number of unread samples stored in FIFO. (000000 = FIFO empty; 100000 = FIFO full, 32 unread samples). |

8.20 TAP_THS_X (30h)

Enables 4D configuration and configures TAP threshold (R/W)

Table 58. TAP_THS_X register

| | | | | | | | |
|-------|---------|---------|------------|------------|------------|------------|------------|
| 4D_EN | 6D_THS1 | 6D_THS0 | TAP_THSX_4 | TAP_THSX_3 | TAP_THSX_2 | TAP_THSX_1 | TAP_THSX_0 |
|-------|---------|---------|------------|------------|------------|------------|------------|

Table 59. TAP_THS_X register description

| | |
|----------------|---|
| 4D_EN | Enables 4D detection portrait/landscape position (0: no position detected; 1: portrait/landscape detection and face-up/face-down position enabled). |
| 6D_THS[1:0] | Thresholds for 4D/6D function @ FS = ± 2 g (refer to Table 60. 4D/6D threshold setting FS @ ± 2 g) |
| TAP_THSX_[4:0] | Threshold for TAP recognition @ FS = ± 2 g on X direction |

Table 60. 4D/6D threshold setting FS @ ± 2 g

| 6D_THS[1:0] | Threshold decoding (degrees) |
|-------------|------------------------------|
| 00 | 6 (80 degrees) |
| 01 | 11 (70 degrees) |
| 10 | 16 (60 degrees) |
| 11 | 21 (50 degrees) |

8.21 TAP_THS_Y (31h)

Table 61. TAP_THS_Y register

| | | | | | | | |
|-------------|-------------|-------------|------------|------------|------------|------------|------------|
| TAP_PRIOR_2 | TAP_PRIOR_1 | TAP_PRIOR_0 | TAP_THSY_4 | TAP_THSY_3 | TAP_THSY_2 | TAP_THSY_1 | TAP_THSY_0 |
|-------------|-------------|-------------|------------|------------|------------|------------|------------|

Table 62. TAP_THS_Y register description

| | |
|-----------------|--|
| TAP_PRIOR_[2:0] | Selection of priority axis for tap detection (see Table 63. Selection of axis priority for tap detection) |
| TAP_THSY_[4:0] | Threshold for tap recognition @ FS = ± 2 g on Y direction |

Table 63. Selection of axis priority for tap detection

| TAP_PRIOR_[2:0] | Max priority | Mid priority | Min priority |
|-----------------|--------------|--------------|--------------|
| 000 | X | Y | Z |
| 001 | Y | X | Z |
| 010 | X | Z | Y |
| 011 | Z | Y | X |
| 100 | X | Y | Z |
| 101 | Y | Z | X |
| 110 | Z | X | Y |
| 111 | Z | Y | X |

8.22 TAP_THS_Z (32h)

Table 64. TAP_THS_Z register

| | | | | | | | |
|----------|----------|----------|------------|------------|------------|------------|------------|
| TAP_X_EN | TAP_Y_EN | TAP_Z_EN | TAP_THSZ_4 | TAP_THSZ_3 | TAP_THSZ_2 | TAP_THSZ_1 | TAP_THSZ_0 |
|----------|----------|----------|------------|------------|------------|------------|------------|

Table 65. TAP_THS_Z register description

| | |
|----------------|---|
| TAP_X_EN | Enables X direction in tap recognition (0: disabled; 1: enabled) |
| TAP_Y_EN | Enables Y direction in tap recognition (0: disabled; 1: enabled) |
| TAP_Z_EN | Enables Z direction in tap recognition (0: disabled; 1: enabled) |
| TAP_THSZ_[4:0] | Threshold for tap recognition @ FS = ± 2 g on Z direction |

8.23 INT_DUR (33h)

Interrupt duration register (R/W)

Table 66. INT_DUR register

| LATENCY3 | LATENCY2 | LATENCY1 | LATENCY0 | QUIET1 | QUIET0 | SHOCK1 | SHOCK0 |
|----------|----------|----------|----------|--------|--------|--------|--------|
|----------|----------|----------|----------|--------|--------|--------|--------|

Table 67. INT_DUR register description

| | |
|--------------|--|
| LATENCY[3:0] | Duration of maximum time gap for double-tap recognition. When double-tap recognition is enabled, this register expresses the maximum time between two successive detected taps to determine a double-tap event. Default value is LATENCY[3:0] = 0000 (which is $16 * 1/ODR$) 1 LSB = $32 * 1/ODR$ |
| QUIET[1:0] | Expected quiet time after a tap detection: this register represents the time after the first detected tap in which there must not be any overthreshold event. Default value is QUIET[1:0] = 00 (which is $2 * 1/ODR$) 1 LSB = $4 * 1/ODR$ |
| SHOCK[1:0] | Maximum duration of overthreshold event: this register represents the maximum time of an overthreshold signal detection to be recognized as a tap event. Default value is SHOCK[1:0] = 00 (which is $4 * 1/ODR$) 1 LSB = $8 * 1/ODR$ |

8.24 WAKE_UP_THS (34h)

Wake-up threshold register (R/W)

Table 68. WAKE_UP_THS register

| SINGLE_ DOUBLE_ TAP | SLEEP_ON | WK_THS5 | WK_THS4 | WK_THS3 | WK_THS 2 | WK_THS 1 | WK_THS 0 |
|---------------------|----------|---------|---------|---------|----------|----------|----------|
|---------------------|----------|---------|---------|---------|----------|----------|----------|

Table 69. WAKE_UP_THS register description

| | |
|-------------------|---|
| SINGLE_DOUBLE_TAP | Enables single/double-tap event. Default value: 0 (0: only single-tap event is enabled; 1: single and double-tap events are enabled) |
| SLEEP_ON | Enables sleep (inactivity). Default value: 0 (0: sleep disabled; 1: sleep enabled) |
| WK_THS[5:0] | Wake-up threshold, 6-bit unsigned 1 LSB = $1/64$ of FS. Default value: 000000 |

8.25 WAKE_UP_DUR (35h)

Wake-up and sleep duration configuration register (R/W)

Table 70. WAKE_UP_DUR register

| | | | | | | | |
|---------|-----------|-----------|------------|------------|------------|------------|------------|
| FF_DUR5 | WAKE_DUR1 | WAKE_DUR0 | STATIONARY | SLEEP_DUR3 | SLEEP_DUR2 | SLEEP_DUR1 | SLEEP_DUR0 |
|---------|-----------|-----------|------------|------------|------------|------------|------------|

Table 71. WAKE_UP_DUR register description

| | |
|----------------|---|
| FF_DUR5 | Free-fall duration. In conjunction with FF_DUR [4:0] bit in the FREE_FALL (36h) register. 1 LSB = $1 * 1/ODR$ |
| WAKE_DUR[1:0] | Wake-up duration. 1 LSB = $1 * 1/ODR$ |
| STATIONARY | Enables stationary detection / motion detection with no automatic ODR change when detecting stationary state Default value: 0 (0: disabled; 1: enabled) |
| SLEEP_DUR[3:0] | Duration to go in sleep mode Default value is SLEEP_DUR[3:0] = 0000 (which is $16 * 1/ODR$). 1 LSB = $512 * 1/ODR$ |

8.26 FREE_FALL (36h)

Free-fall duration and threshold configuration register (R/W)

Table 72. FREE_FALL register

| | | | | | | | |
|---------|---------|---------|---------|---------|---------|---------|---------|
| FF_DUR4 | FF_DUR3 | FF_DUR2 | FF_DUR1 | FF_DUR0 | FF_THS2 | FF_THS1 | FF_THS0 |
|---------|---------|---------|---------|---------|---------|---------|---------|

Table 73. FREE_FALL register description

| | |
|--------------|---|
| FF_DUR [4:0] | Free-fall duration. In conjunction with FF_DUR5 bit in the WAKE_UP_DUR (35h) register. 1 LSB = $1 * 1/ODR$ |
| FF_THS [2:0] | Free-fall threshold @ FS = $\pm 2 g$ (refer to Table 74. FREE_FALL threshold decoding @ $\pm 2 g$ FS) |

Table 74. FREE_FALL threshold decoding @ $\pm 2 g$ FS

| FF_THS[2:0] | Threshold decoding (LSB) |
|-------------|--------------------------|
| 000 | 5 |
| 001 | 7 |
| 010 | 8 |
| 011 | 10 |
| 100 | 11 |
| 101 | 13 |
| 110 | 15 |
| 111 | 16 |

8.27 STATUS_DUP (37h)

Event detection status register (R)

Table 75. STATUS_DUP register

| OVR | DRDY_T | SLEEP_STATE_IA | DOUBLE_TAP | SINGLE_TAP | 6D_IA | FF_IA | DRDY |
|-----|--------|----------------|------------|------------|-------|-------|------|
|-----|--------|----------------|------------|------------|-------|-------|------|

Table 76. STATUS_DUP register description

| | |
|----------------|--|
| OVR | FIFO overrun status flag (0: FIFO is not completely filled; 1: FIFO is completely filled and at least one sample has been overwritten) |
| DRDY_T | Temperature status (0: data not available; 1: a new set of data is available) |
| SLEEP_STATE_IA | Sleep event status (0: Sleep event not detected; 1: Sleep event detected) |
| DOUBLE_TAP | Double-tap event status (0: Double-tap event not detected; 1: Double-tap event detected) |
| SINGLE_TAP | Single-tap event status (0: Single-tap event not detected; 1: Single-tap event detected) |
| 6D_IA | Source of change in position portrait/landscape/face-up/face-down (0: no event detected; 1: a change in position is detected) |
| FF_IA | Free-fall event detection status (0: free-fall event not detected; 1: free-fall event detected) |
| DRDY | Data-ready status (0: not ready; 1: X-, Y-, and Z-axis new data available) |

8.28 WAKE_UP_SRC (38h)

Wake-up source register (R)

Table 77. WAKE_UP_SRC register

| | | | | | | | |
|---|---|-------|----------------|-------|------|------|------|
| 0 | 0 | FF_IA | SLEEP_STATE IA | WU_IA | X_WU | Y_WU | Z_WU |
|---|---|-------|----------------|-------|------|------|------|

Table 78. WAKE_UP_SRC register description

| | |
|----------------|--|
| FF_IA | Free-fall event detection status (0: FF event not detected; 1: FF event detected) |
| SLEEP_STATE IA | Sleep event status (0: sleep event not detected; 1: sleep event detected) |
| WU_IA | Wake-up event detection status (0: wake-up event not detected; 1: wake-up event is detected) |
| X_WU | Wake-up event detection status on X-axis (0: wake-up event on X not detected; 1: wake-up event on X-axis is detected) |
| Y_WU | Wake-up event detection status on Y-axis (0: wake-up event on Y not detected; 1: wake-up event on Y-axis is detected) |
| Z_WU | Wake-up event detection status on Z-axis (0: wake-up event on Z not detected; 1: wake-up event on Z-axis is detected) |

8.29 TAP_SRC (39h)

Tap source register (R)

Table 79. TAP_SRC register

| | | | | | | | |
|---|--------|------------|------------|----------|-------|-------|-------|
| 0 | TAP_IA | SINGLE_TAP | DOUBLE_TAP | TAP_SIGN | X_TAP | Y_TAP | Z_TAP |
|---|--------|------------|------------|----------|-------|-------|-------|

Table 80. TAP_SRC register description

| | |
|------------|--|
| TAP_IA | Tap event status (0: tap event not detected; 1: tap event detected) |
| SINGLE_TAP | Single-tap event status (0: single-tap event not detected; 1: single-tap event detected) |
| DOUBLE_TAP | Double-tap event status (0: double-tap event not detected; 1: double-tap event detected) |
| TAP_SIGN | Sign of acceleration detected by tap event (0: positive sign of acceleration detected; 1: negative sign of acceleration detected) |
| X_TAP | Tap event detection status on X-axis (0: tap event on X not detected; 1: tap event on X-axis is detected) |
| Y_TAP | Tap event detection status on Y-axis (0: tap event on Y not detected; 1: tap event on Y-axis is detected) |
| Z_TAP | Tap event detection status on Z-axis (0: tap event on Z not detected; 1: tap event on Z-axis is detected) |

8.30
SIXD_SRC (3Ah)

6D source register (R)

Table 81. SIXD_SRC register

| | | | | | | | |
|---|-------|----|----|----|----|----|----|
| 0 | 6D_IA | ZH | ZL | YH | YL | XH | XL |
|---|-------|----|----|----|----|----|----|

Table 82. SIXD_SRC register description

| | |
|-------|--|
| 6D_IA | Source of change in position portrait/landscape/face-up/face-down (0: no event detected; 1: a change in position is detected) |
| ZH | ZH over threshold (0: ZH does not exceed the threshold; 1: ZH is over the threshold) |
| ZL | ZL over threshold (0: ZL does not exceed the threshold; 1: ZL is over the threshold) |
| YH | YH over threshold (0: YH does not exceed the threshold; 1: YH is over the threshold) |
| YL | YL over threshold (0: YL does not exceed the threshold; 1: YL is over the threshold) |
| XH | XH over threshold (0: XH does not exceed the threshold; 1: XH is over the threshold) |
| XL | XL over threshold (0: XL does not exceed the threshold; 1: XL is over the threshold) |

8.31 ALL_INT_SRC (3Bh)

Reading this register, all related interrupt function flags routed to the INT pads are reset simultaneously.

Table 83. ALL_INT_SRC register

| | | | | | | | |
|---|---|-----------------|-------|------------|------------|-------|-------|
| 0 | 0 | SLEEP_CHANGE_IA | 6D_IA | DOUBLE_TAP | SINGLE_TAP | WU_IA | FF_IA |
|---|---|-----------------|-------|------------|------------|-------|-------|

Table 84. ALL_INT_SRC register description

| | |
|-----------------|---|
| SLEEP_CHANGE_IA | Sleep change status (0: sleep change not detected; 1: sleep change detected) |
| 6D_IA | Source of change in position portrait/landscape/face-up/face-down (0: no event detected; 1: a change in position detected) |
| DOUBLE_TAP | Double-tap event status (0: double-tap event not detected; 1: double-tap event detected) |
| SINGLE_TAP | Single-tap event status (0: single-tap event not detected; 1: single-tap event detected) |
| WU_IA | Wake-up event detection status (0: wake-up event not detected; 1: wake-up event detected) |
| FF_IA | Free-fall event detection status. (0: free-fall event not detected; 1: free-fall event detected) |

8.32 X_OFS_USR (3Ch)

Table 85. X_OFS_USR register

| | | | | | | | |
|-------------|-------------|-------------|-------------|-------------|-------------|-------------|-------------|
| X_OFS_USR_7 | X_OFS_USR_6 | X_OFS_USR_5 | X_OFS_USR_4 | X_OFS_USR_3 | X_OFS_USR_2 | X_OFS_USR_1 | X_OFS_USR_0 |
|-------------|-------------|-------------|-------------|-------------|-------------|-------------|-------------|

Table 86. X_OFS_USR register description

| | |
|----------------|--|
| X_OFS_USR[7:0] | Two's complement user offset value on X-axis data, used for wake-up function |
|----------------|--|

8.33 Y_OFS_USR (3Dh)

Table 87. Y_OFS_USR register

| | | | | | | | |
|-------------|-------------|-------------|-------------|-------------|-------------|-------------|-------------|
| Y_OFS_USR_7 | Y_OFS_USR_6 | Y_OFS_USR_5 | Y_OFS_USR_4 | Y_OFS_USR_3 | Y_OFS_USR_2 | Y_OFS_USR_1 | Y_OFS_USR_0 |
|-------------|-------------|-------------|-------------|-------------|-------------|-------------|-------------|

Table 88. Y_OFS_USR register description

| | |
|----------------|--|
| Y_OFS_USR[7:0] | Two's complement user offset value on Y-axis data, used for wake-up function |
|----------------|--|

8.34 Z_OFS_USR (3Eh)

Table 89. Z_OFS_USR register

| | | | | | | | |
|-------------|-------------|-------------|-------------|-------------|-------------|-------------|-------------|
| Z_OFS_USR_7 | Z_OFS_USR_6 | Z_OFS_USR_5 | Z_OFS_USR_4 | Z_OFS_USR_3 | Z_OFS_USR_2 | Z_OFS_USR_1 | Z_OFS_USR_0 |
|-------------|-------------|-------------|-------------|-------------|-------------|-------------|-------------|

Table 90. Z_OFS_USR register description

| | |
|----------------|--|
| Z_OFS_USR[7:0] | Two's complement user offset value on Z-axis data, used for wake-up function |
|----------------|--|

8.35 CTRL7 (3Fh)

Table 91. CTRL7 register

| | | | | | | | |
|-------------|--------------|-------------------|----------------|---------------|-----------|-------------|------------|
| DRDY_PULSED | INT2_ON_INT1 | INTERRUPTS_ENABLE | USR_OFF_ON_OUT | USR_OFF_ON_WU | USR_OFF_W | HP_REF_MODE | LPASS_ON6D |
|-------------|--------------|-------------------|----------------|---------------|-----------|-------------|------------|

Table 92. CTRL7 register description

| | |
|-------------------|--|
| DRDY_PULSED | Switches between latched and pulsed mode for data ready interrupt (0: latched mode is used; 1: pulsed mode enabled for data-ready) |
| INT2_ON_INT1 | Signal routing (1: all signals available only on INT2 are routed to INT1) |
| INTERRUPTS_ENABLE | Enables interrupts |
| USR_OFF_ON_OUT | Enables application of user offset value in accelerometer output data registers FDS bit in CTRL6 (25h) must be set to 0 logic (low-pass path selected). |
| USR_OFF_ON_WU | Enables application of user offset value on accelerometer data for wake-up function only |
| USR_OFF_W | Selects the weight of the user offset words specified by X_OFS_USR_[7:0], Y_OFS_USR_[7:0], and Z_OFS_USR_[7:0] bits (0: 977 μ g/LSB; 1: 15.6 mg/LSB) |
| HP_REF_MODE | Enables high-pass filter reference mode (0: high-pass filter reference mode disabled (default); 1: high-pass filter reference mode enabled) |
| LPASS_ON6D | (0: ODR/2 low-pass filtered data sent to 6D interrupt function (default); 1: LPF2 output data sent to 6D interrupt function) |

9 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

9.1 Soldering information

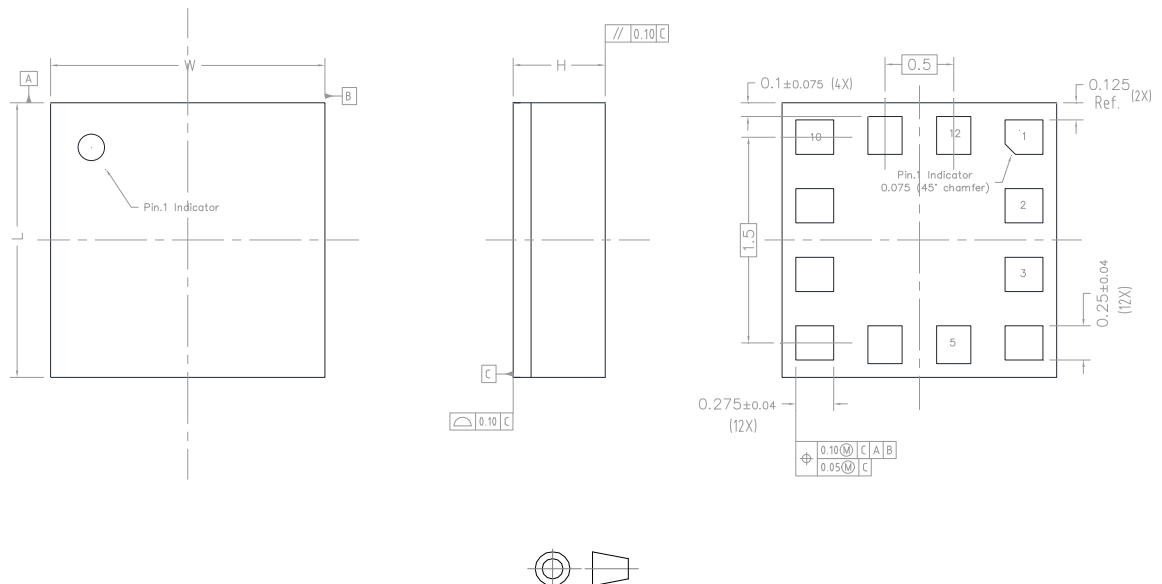
The LGA package is compliant with the ECOPACK and RoHS standard.

It is qualified for soldering heat resistance according to JEDEC J-STD-020.

For land pattern and soldering recommendations, consult technical note [TN0018](#) available on www.st.com.

9.2 LGA-12L package information

Figure 18. LGA-12L 2.0 x 2.0 x 0.7 mm package outline and mechanical data



Dimensions are in millimeter unless otherwise specified.
General Tolerance is ± 0.15 mm unless otherwise specified.

OUTER DIMENSIONS

| ITEM | DIMENSION [mm] | TOLERANCE [mm] |
|------------|----------------|----------------|
| Length [L] | 2 | ± 0.1 |
| Width [W] | 2 | ± 0.1 |
| Height [H] | 0.7 MAX | / |

DM00170568_7

Note: Package tolerances guaranteed by process

9.3 LGA-12L packing information

Figure 19. Carrier tape information for LGA-12L package

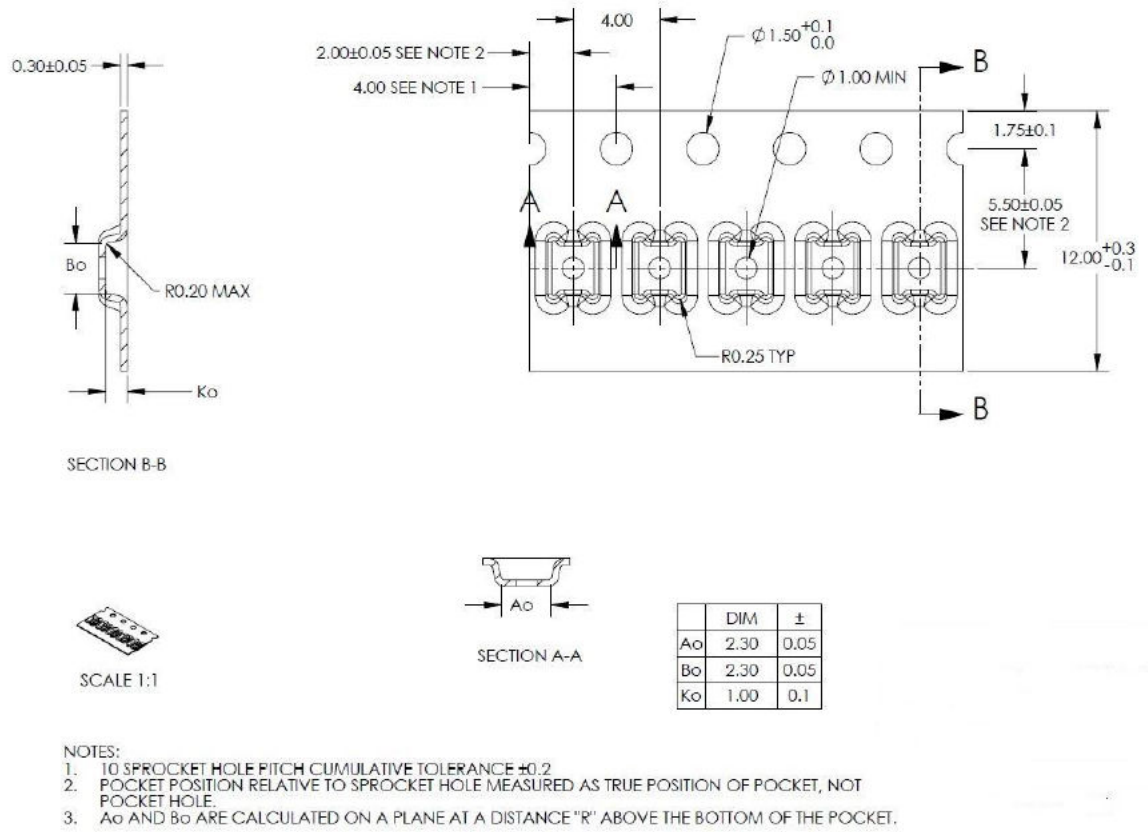
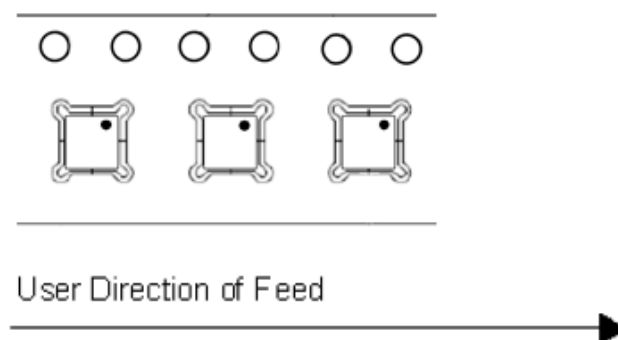


Figure 20. LGA-12L package orientation in carrier tape



Revision history

Table 93. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 10-Feb-2017 | 1 | Initial release |
| 13-Apr-2017 | 2 | Updated Applications and Figure 7: Accelerometer chain Added Section 3.2.4: Activity/Inactivity, Android stationary/motion-detection functions Renamed registers 3Ch, 3Dh, 3Eh, 3Fh |
| 15-Jun-2017 | 3 | Added bullet concerning Android to Features |
| 12-Sep-2017 | 4 | Document status promoted to "production data" Updated Description Updated Section 3.2.4: Activity/Inactivity, Android stationary/motion-detection functions Added bit 7 to CTRL5_INT2_PAD_CTRL (24h) Added bit 4 to WAKE_UP_DUR (35h) |
| 01-Oct-2018 | 5 | Added product label indicating participation in ST's sustainable technology program |
| 06-Nov-2018 | 6 | Updated Section 3.2.4 Activity/Inactivity, Android stationary/motion-detection functions Updated Figure 6. LIS2DW12 electrical connections (top view) Added Section 9.3 LGA-12 packing information |
| 03-May-2019 | 7 | Updated Figure 19. Carrier tape information for LGA-12 package |
| 02-Jul-2019 | 8 | Updated OUT_T_L (0Dh) and OUT_T_H (0Eh) |
| 17-Sep-2024 | 9 | Updated product summary Added quick links to product resources Updated V_{IH} and V_{IL} in Table 4. Electrical characteristics as well as Notes below Figure 3. SPI slave timing diagram and Figure 4. I ² C slave timing diagram Minor textual updates |

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